



SPIRE Document

PFM5 WARM FUNCTIONAL TEST REPORT Redundant Side A.A.Aramburu

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1. Introduction

This document reports on the WARM FUNCTIONAL TESTS carried out on the SPIRE Flight Instrument Model at the start of the PFM5 ILT tests campaign to verify the correct functioning of each of its subsystems prior to cool down. The test cryostat chamber was fully pumped down.

1.1 Scope

To judge the success or failure of a warm functional test by checking that:

- The telecommand sequence generated for a particular functional test is correctly received and executed on board by the SPIRE DPU.
- No error/event reports or command failures are generated during the execution of these commands.
- Telemetry is generated by the instrument as a result of telemetry requests to its different subunits.
- Particular telemetry parameters for each functional test change in an expected manner.
- A particular success criterion/criteria (specified in this document) is/are met.

1.2 Reference Documents

Ref	Document	Name	Version/Issue Nb.
RD01	SPIRE-RAL-DOC-001652	SPIRE Functional Tests Specification	Issue 1.4
RD02	SPIRE-RAL-DOC-001630	SPIRE EGSE-ILT Start-Up Procedures	Issue 0.7
RD03	SPIRE-RAL-PRC-002222	DRCU Switch ON Procedure	Issue 1.0
RD04	SPIRE-RAL-PRJ-001078	SPIRE Data ICD	Issue 2.0
RD05	Sap-SPIRE-CCa-076-02	DRCU/DPU Interface Control Document	Issue 1.2
RD06	LAM.PJT.SPI.NOT.011011	MCU/DPU Command List ICD	Issue 5.0
RD07	SPIRE-IFS-PRJ-001391	SPIRE OBS User Manual	Issue 2.2
RD08	SPIRE-IFS-PRJ-000650	SPIRE DPU Interface Control Document	Issue 1.1

1.3 Change Record

Document	Change date	Changes
Issue 1.0	3 rd January 2007	First version of the document created.



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2. Functional Tests Configuration

2.1 SPIRE Instrument Configuration (REDUNDANT)

SPIRE FPU:

- FPU In Tank.
- DRCU to Cryostat harnesses connected (Grounding pins not connected)
- Cryostat open
- Cryo-harness connected to FPU

SPIRE FM DPU:

- DPU Power supply connected on DPU Power REDUNDANT (J01) connector (DPU side).
- 1553 Mil Bus connected on REDUNDANT Connector Bus A (J03) connector (DPU side).
- DPU-DRCU REDUNDANT interfaces connected:

SPIRE FM DRCU:

- DRCU Power supply connected on DRCU Power REDUNDANT (J05) connector (DRCU side on FCU) via the external DRCU switch box.
- FCU to DCU REDUNDANT power connector J7 (FCU) to J03 (DCU) via the external DPU switch box.

2.2 Software Configuration (REDUNDANT)

The current EGSE software configuration for the REDUNDANT side tests:

EGSE component	Version/Build number	Comment
SCOS2000	SCOS2.3e Patch 5	SCOS archives PFM4_TEST3_PRIME under /spired/hfiles and /spired/TMD SCOS MIB is PFM4_Issue2.2.D1_Redundant
CDMS Simulator	v2.5	
HCSS	v0.3.6 Build #1043	
QLA	3.2.3 Build #438	
QLA scripts	?	
Test Control scripts	Create TAGS	
CUS Scripts	Create TAGS	
Versant	7.0.0.1	
TFCS	MIB v1.9 Code	
TFTS	MIB v1.6 Server code v1.6	



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2.3 EGSE Configuration Checks

To check for the success of failure of a functional test, the real time telemetry of the instrument has to be monitored. The following applications must be running to do so. Before the test sequence starts, make the following checks:

Workstation	EGSE component	Status	Check	Comments
Lichfield	EGSE router	Started	✓	Running in the background – no dedicated console on lichfield
Lichfield	EGSE Gateway	Started	✓	Running in the background – no dedicated console on lichfield
Lichfield	Telemetry Ingestion	Started	✓	Running
Lichfield	Packet Display	Started	✓	Running
Lincoln	SCOS2000	Started	✓	Running
Lincoln	EXIF + TOPE	Started	✓	Running
Lincoln	Manual Stack	Started	✓	Running
Gordon	CDMS Simulator	Started	✓	Running
Lichfield	Test Control Server	Started	✓	Running

The following checks were performed to verify the correct initial instrument configuration for the tests.

Step#	Action	Comments	Check
1	In SCOS open DPU_AND_OBS_PARAMETERS display Check if: TM2N is incrementing by one @1Hz. TM1N is incrementing by one @0.5Hz. - If they are, go to step 5. - If they are not, go to step 2.	Both TM1N and TM2N are incrementing at their nominal rates. Will go to step 5.	✓
2	Check if the DPU is powered ON: - If ON, the DPU power supply LCD will show ~ 28V and 0.40A, go to step 4. - If not ON, power ON DPU see comments on the right, then go to step 3.		
3	In SCOS open Boot_ROM_Memory_Check display and check no errors are reported: - If no errors are reported, execute		



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	DPU_ON from HCSS Test Procedures. Then repeat step 1. - If the (5,1) contains errors: Check the error code in RD07. Then switch OFF the DPU and repeat step 2		
4	Execute define_new_HK_report.tcl HCSS Test procedure.		
5	In SCOS open SCU_PARAMETERS display - If SCUP5V/P9V/M9V are jittering and BIAS_PARAMETERS display - If BIASTEMP show ambient temperature, the DRCU is ON.Go to step 6. - If DRCU is not ON, refer to RD03 on how to start up the DRCU.	ALL SCU VOLTAGES LOOKING GOOD. SCUP5V = 5.22V SCUP9V =9.09V SCUM9V = -9.10V ALL BIAS VOLTAGES LOOKING GOOD. BIASP5V = 5.10V BIASP9V = 9.00V BIASM9V= -9.06V	✓
6	In SCOS open DPU_AND_OBS_PARAMETERS display and check that the MODE housekeeping parameter is DRCU_ON.	MODE (RAW)= 0x100 MODE (ENG) = DRCU_ON	✓

Table 1. Initial configuration check



3. Test procedure

The following two sections describe general pass/fail criteria (Section 3.1), the general test procedure layout (Section 3.1) and the detailed procedure for each functional test (Section 3.2).

3.1 General Pass/Fail Criteria

The general criterion for declaring a single test failed is the repeated failure of 2 consecutive runs of this test. In that case the functional test procedure should be aborted and the overall functional testing declared FAILED.

In the case of a 'first run' failure followed by a successful execution a third run of the same test should be performed and in the unlikely event of this third run being a failure the test procedure should be also aborted and the overall functional testing declared FAILED, as this would imply a not reliable operability of the instrument.

As a general remark ANY failure should be closely analyzed.

Note: If the functional test is declared FAILED refer to section 4.1 for instrument switch OFF.

3.2 General Test Sequence

The table below shows the general WFT as it was performed.

Step	Subsystem tested	Test Id	Test Purpose
1	SCU	FUNC-SCU-01	SCU Nominal Science Generation Check
2		FUNC-SCU-03	FPU DC Thermometry Check
3		FUNC-SCU-06	FPU AC Thermometry Check
4		FUNC-SCU-02	SCU Nominal Science Contents Check
5		FUNC-SCU-08	SCU Test Pattern Check
6		FUNC-SCU-07	Sorption Cooler Check
7		FUNC-SCU-04	Photometer Calibrator Check
8		FUNC-SCU-05	Spectrometer Calibrators Check
9	MCU	FUNC-MCU-01	MCU Boot Check
10		FUNC-MCU-02	MCU Nominal Science Generation Check
11		FUNC-MCU-03	MCU Nominal Science Contents Check
12		FUNC-MCU-04	MCU Test Pattern Check
13	BSMm	FUNC-BSM-01	BSM Switch ON Check
14		FUNC-BSM-02c	BSM Chop Sensor Polarity Check
15		FUNC-BSM-02j	BSM Jiggle Sensor Polarity Check
16		FUNC-BSM-03	BSM Open Loop dynamics Check
17		BSM_INIT	Close loop on chop/jiggle axis.
18		FUNC-BSM-06	BSM Operational Mode Check
19	DCU	FUNC-DCU-01	DCU Nominal Science Generation Check
20		FUNC-DCU-02	DCU Nominal Science Contents Check
21		FUNC-DCU-03	DCU Test Pattern Check
22	Photometer LIAs	FUNC-DCU-04P	Photometer LIAs Check
23		FUNC-DCU-05P	Photometer Manual Offset Setting Check
24		FUNC-DCU-11P	Photometer Detectors Switch ON Check



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25	Photometer BDAs	FUNC-DCU-013P	Photometer Detectors Check
26	Spectrometer LIAs	FUNC-DCU-04S	Spectrometer LIAs Check
27		FUNC-DCU-05S	Spectrometer Manual Offset Setting Check
28		FUNC-DCU-11S	Spectrometer Detectors Switch ON Check
29	Spectrometer BDAs	FUNC-DCU-013S	Spectrometer Detectors Check
18	SMECm	FUNC-SMEC-02A	SMEC Launch Latch Open/Close Check
19		FUNC-SMEC-01	SMECm Switch ON Check
20		FUNC-SMEC-03	SMEC LED Optical Encoder LED Check
21		FUNC-SMEC-04	SMEC Positioning Test (Open Loop)

Table 2. General WFT sequence



4. Detailed Test Results on REDUNDANT instrument.

The following is a detailed (test by test) procedure including the steps performed on each test and the results obtained.

Step#	Action	Comments
0	Open SCU_PARAMETERS display on SCOS Alpha Numeric Displays.	

4.1 FUNC-SCU-01

Test Id:	FUNC-SCU-01												
Initial Configuration:	DRCU_ON												
Final Configuration:	DRCU_ON												
Success Criteria:	<p>Test passed if :</p> <ol style="list-style-type: none"> Two SCU Nominal Science Report telemetry packets are received on QLA with the following characteristics: <table border="1" style="margin-left: 40px;"> <thead> <tr> <th>APID</th> <th>Type</th> <th>Subtype</th> <th>SID</th> <th>FrameID</th> <th>Frame length</th> </tr> </thead> <tbody> <tr> <td style="text-align: center;">0x509</td> <td style="text-align: center;">21</td> <td style="text-align: center;">1</td> <td style="text-align: center;">0xA20</td> <td style="text-align: center;">0x20</td> <td style="text-align: center;">0x1E</td> </tr> </tbody> </table> <ol style="list-style-type: none"> The frame time difference between consecutive SCU frames within these packets corresponds to the sampling rate. Nominal SCU sampling rate is 80Hz → Δt = 12.5 ms The SPIRE HK parameter SCUFRAMECNT increments by 31. No events are generated during the frame generation. <p>QLA to give go ahead.</p>	APID	Type	Subtype	SID	FrameID	Frame length	0x509	21	1	0xA20	0x20	0x1E
APID	Type	Subtype	SID	FrameID	Frame length								
0x509	21	1	0xA20	0x20	0x1E								

Test Procedure:

Step#	Action	Comments
1	Write the initial value of SCUFRAMECNT parameter located in SCU_PARAMETERS display and the initial value of TM1N located in DPU_AND-OBS_PARAMETERS display.	SCUFRAMCNT = 0
2	Run QLA script FUNC-SCU-01.py on QLA console.	
3	Run FUNC-SCU-01 test procedure from the HCSS Test Procedure window on TOPE	
4	Write the final value of SCUFRAMECNT and TM1N.	SCUFRAMCNT = 31
5	Contingency: If test fails repeat steps 1 to 4.	

Test Log:



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Test Id	Key Parameter(s)	Expected Value Before/After	Actual Value Before/After	Nb. of frames received	Test Result
FUNC-SCU-01	SCUFRAMECNT TM5N	n/ n+ 31 0x3FFF/1	0/ 31 0x3FFF/1	31	Success

Start time @: 12:29
End time @: 12: 29
OBSID: 0x30011A8D
Comments:

QLA script was run in playback:

```
*****
SCU: OBSID = 30011A8D, BBTYPE = 0x8000, APID = 0x509, SID = 0xa20
-----
Parameter      Initial      Final      Increment Expect Incre. Packet Chars.
SCUFRAMECNT    0            31         31         31         Packet type = 0x15
TM5N           16383        1          49153      2          subtype = 0x1
FrameTime      12.4960     12.4960
Frame ID       = 0x20
Frame Len      = 0x1E
STATISTICS ON TIME BETWEEN RECEPTION OF 2 CONSECUTIVE FRAMES:
mean = 12.49792 ms
sigma = 0.00160 ms
```



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4.2 FUNC-SCU-03

Test Id:	FUNC-SCU-03
Initial Configuration:	DRCU_ON
Final Configuration:	DRCU_ON + DC thermometry ON
Success Criteria:	<p>Test passed if all FPU DC thermometry sensors show temperature values indicating a correct functioning of the sensor, not open/short-circuited. If ANY reading is anomalous check RAW sensor reading.</p> <p>Open Circuit Criterion: RAW reading in the range [0, -100]</p> <p>Short Circuit Criterion: RAW reading of -32768</p> <p>Note: For some parameters the calibration curve above 75K has only 2 points, thus the linearly interpolated temperature reading given by SCOS is usually not correct at T > 75K.</p>

Test Procedure:

Step#	Action	Comments
1	Run FUNC-SCU-03 test procedure from the HCSS Test Procedure window on TOPE	
2	When the test is finished Write the current value of SCUTEMPSTAT and the RAW/converted values of the 16 FPU temperatures located in SCU_PARAMETERS display.	
3	Contingency: If test fails execute SCU_OFF procedure from HCSS Test Procedure window on TOPE and then repeat steps 1 and 2.	

Test Log:

Test Id	Key Parameter(s)	Expected Value Before/After	Actual Value Before/After	Nb. of frames received	Test Result
FUNC-SCU-03	SCUTEMPSTAT	0/0xFFFF	0/0xffff	N/A	Success



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Start time @: 12:31

End time @: 12:31

OBSID:0x30011A8E

Comments:

SCU-03 Thermometry Check
OBSID = 0x30011a8e

PUMPHRTEMP	50.09	32768
PUMPHSTEMP	36.42	32768
EVAPHSTMP	39.25	32768
SHUNTTEMP	18.05	32768
EMCFILTMP	284.27	35977
SL0TEMP	19.89	32768
PL0TEMP	22.52	32768
OPTTEMP	141.72	32768
BAFTEMP	160.50	32768
BSMIFTEMP	110.81	32768
SCAL2TEMP	166.07	32768
SCAL4TEMP	141.47	32768
SCALTEMP	83.15	32768
SMECIFTEMP	133.33	32768
SMECTEMP	27.28	32768
BSMTEMP	13.13	32768

The actual SCOS display readings are -32768. Error on QLA script?



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4.3 FUNC-SCU-06

Test Id:	FUNC-SCU-06
Initial Configuration:	DRCU_ON + DC thermometry ON
Final Configuration:	DRCU_ON + AC/DC thermometry ON
Success Criteria:	Test passed if SUBKSTAT parameter went from 0 to 1. Open Circuit Criterion: RAW reading in the range 0 -100 Short Circuit Criterion: RAW reading of -32768

Test Procedure:

Step#	Action	Comments
1	Run FUNC-SCU-06 test procedure from the HCSS Test Procedure window on TOPE.	
2	When the test is finished Write the current value of SUBKSTAT located in SCU_PARAMETERS display. Also write down the RAW value of the SUBKTEMP parameter.	
3	Contingency: If test fails : Send manual command: SEND_DRCU_COMMAND Parameter1 = 0xA0860000 Parameter2 = 0 Then repeat steps 1 and 2.	

Test Log:

Test Id	Key Parameter(s)	Expected Value Before/After	Actual Value Before/After	Nb. of frames received	Test Result
FUNC-SCU-06	SUBKSTAT	0/1	0/1	N/A	Success



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Start time @: 12:43

End time @: 12:43

OBSID:0x30011A8F

Comments:

SUBKTEMP:

Before: RAW = 32767

After : RAW = 32767

No change (as it happened) on PFM4 but the channel is actually working.



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4.4 FUNC-SCU-02

Test Id:	FUNC-SCU-02
Initial Configuration:	DRCU_ON + AC/DC thermometry ON
Final Configuration:	DRCU_ON + AC/DC thermometry ON
Success Criteria:	Test passed if : <ol style="list-style-type: none"> 1. Parameters in the SCU Nominal science packets and the same parameters in the Nominal HK packet have similar RAW/converted values to within 10%. 2. The SPIRE HK parameter SCUFRAMECNT located in SCU_PARAMETERS display increments by 31. 3. No events are generated during the frame generation. QLA to give the go ahead.

Test Procedure:

Step#	Action	Comments
1	Write the current value of SCUFRAMECNT located in SCU_PARAMETERS display.	
2	Run QLA script FUNC-SCU-02.py on QLA console.	
3	Run FUNC-SCU-02 test procedure from the HCSS Test Procedure window on TOPE	
4	When the test is finished Write the current value of SCUFRAMCNT.	
5	Contingency: If test fails repeat steps 1 to 4.	

Test Log:

Test Id	Key Parameter(s)	Expected Value Before/After	Actual Value Before/After	Nb. of frames received	Test Result
FUNC-SCU-02	SCUFRAMECNT TMSN	n+31/n+62 1/3	31/62 1/3	31	Success



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Start time @: 12:45
End time @: 12:46
OBSID: 0x30011A90

Comments:

QLA script was run in playback:

FUNC-SCU-02 version: 1.4

Housekeeping @ Fri Jan 26 12:45:41 GMT 2007

SCU Science @ Fri Jan 26 12:45:35 GMT 2007

Name	HSK value	SCU value	Equal (within 10)?
TCHTRV	18.0	20.0	False
PCALCURR	9.0	10.0	False
SCAL4CURR	10.0	11.0	True
SCAL2CURR	10.0	10.0	True
PCALV	13.0	13.0	True
SCAL4V	11.0	10.0	True
SCAL2V	10.0	10.0	True
PUMPHTRTEMP	32768.0	32768.0	True
PUMPHSTEMP	32768.0	32768.0	True
EVAPHSTEMP	32768.0	32768.0	True
SHUNTTEMP	32768.0	32768.0	True
EMCFILTEMP	35978.0	35974.0	True
SL0TEMP	32768.0	32768.0	True
PL0TEMP	32768.0	32768.0	True
OPTTEMP	32768.0	32768.0	True
BAFTEMP	32768.0	32768.0	True
BSMIFTEMP	32768.0	32768.0	True
SCAL2TEMP	32768.0	32768.0	True
SCAL4TEMP	32768.0	32768.0	True
SCALTEMP	32768.0	32768.0	True
SMECIFTEMP	32768.0	32768.0	True
SMECTEMP	32768.0	32768.0	True
BSMTEMP	32768.0	32768.0	True
SUBKTEMP	32767.0	32767.0	True



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4.5 FUNC-SCU-08

Test Id:	FUNC-SCU-08												
Initial Configuration:	DRCU_ON + AC/DC thermometry ON												
Final Configuration:	DRCU_ON + AC/DC thermometry ON												
Success Criteria:	<p>Test passed if :</p> <ol style="list-style-type: none"> Two SCU Diagnostic Science Report telemetry packets are received with the following characteristics: <table border="1" style="margin-left: 40px;"> <thead> <tr> <th>APID</th> <th>Type</th> <th>Subtype</th> <th>SID</th> <th>FrameID</th> <th>Frame length</th> </tr> </thead> <tbody> <tr> <td>0x509</td> <td>21</td> <td>3</td> <td>0x1121</td> <td>0x21</td> <td>0x1E</td> </tr> </tbody> </table> <ol style="list-style-type: none"> The SCU Test Pattern agrees with the reference test pattern. QLA to give go ahead. 	APID	Type	Subtype	SID	FrameID	Frame length	0x509	21	3	0x1121	0x21	0x1E
APID	Type	Subtype	SID	FrameID	Frame length								
0x509	21	3	0x1121	0x21	0x1E								

Test Procedure:

Step#	Action	Comments
1	Write the current values of SCUFRAMECNT located in SCU_PARAMETERS display.	
2	Run QLA script FUNC-SCU-08.py on QLA console.	
3	Run FUNC-SCU-08 test procedure from the HCSS Test Procedure window on TOPE	
4	When the test is finished Write the current value of SCUFRAMCNT.	
5	Contingency: If test fails repeat steps 1 to 4.	

Test Log:

Test Id	Key Parameter(s)	Expected Value Before/After	Actual Value Before/After	Nb. of frames received	Test Result
FUNC-SCU-08	SCUFRAMECNT and SCU test pattern frame parameters	n+62/n+93	62/93 93/124	31 31	Success



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Start time @: 12:47
End time @: 12:48
OBSID:0x30011A91

Comments:

QLA produced the following file:

SCU Test Pattern @ Fri Jan 26 12:47:15 GMT 2007
..compared with data from SCU Test Pattern @ Thu Jan 25 13:59:59 GMT 2007, OBSID=0x30011A58

Name	New Value[0]	New Value[20]	Comp Value[0]		Comp Value[20]	
SCUTSTOBSID	8.05378705E8	0.0	8.05378648E8	<--BAD	0.0	--> OK
SCUTSTBBID	2.315714561E9	0.0	2.315714561E9	--> OK	0.0	--> OK
SCUTSTBLKLEN	30.0	30.0	30.0	--> OK	30.0	--> OK
SCUTSTFRAMEID	33.0	33.0	33.0	--> OK	33.0	--> OK
SCUTST001	43690.0	31181.0	43690.0	--> OK	31181.0	--> OK
SCUTST002	21844.0	62363.0	21844.0	--> OK	62363.0	--> OK
SCUTST003	43688.0	59190.0	43688.0	--> OK	59190.0	--> OK
SCUTST004	21840.0	52844.0	21840.0	--> OK	52844.0	--> OK
SCUTST005	43680.0	40153.0	43680.0	--> OK	40153.0	--> OK
SCUTST006	21825.0	14771.0	21825.0	--> OK	14771.0	--> OK
SCUTST007	43650.0	29543.0	43650.0	--> OK	29543.0	--> OK
SCUTST008	21765.0	59086.0	21765.0	--> OK	59086.0	--> OK
SCUTST009	43530.0	52637.0	43530.0	--> OK	52637.0	--> OK
SCUTST010	21524.0	39739.0	21524.0	--> OK	39739.0	--> OK
SCUTST011	43048.0	13943.0	43048.0	--> OK	13943.0	--> OK
SCUTST012	20560.0	27887.0	20560.0	--> OK	27887.0	--> OK
SCUTST013	41120.0	55774.0	41120.0	--> OK	55774.0	--> OK
SCUTST014	16705.0	46012.0	16705.0	--> OK	46012.0	--> OK
SCUTST015	33411.0	26489.0	33411.0	--> OK	26489.0	--> OK
SCUTST016	1287.0	52978.0	1287.0	--> OK	52978.0	--> OK
SCUTST017	2574.0	40420.0	2574.0	--> OK	40420.0	--> OK
SCUTST018	5149.0	15304.0	5149.0	--> OK	15304.0	--> OK
SCUTST019	10298.0	30608.0	10298.0	--> OK	30608.0	--> OK
SCUTST020	20597.0	61216.0	20597.0	--> OK	61216.0	--> OK
SCUTST021	41194.0	56896.0	41194.0	--> OK	56896.0	--> OK
SCUTST022	16852.0	48257.0	16852.0	--> OK	48257.0	--> OK
SCUTST023	33705.0	30978.0	33705.0	--> OK	30978.0	--> OK
SCUTST024	1874.0	61956.0	1874.0	--> OK	61956.0	--> OK
SCUTSTADCFGLS	0.0	0.0	0.0	--> OK	0.0	--> OK
SCUTSTFRAMETIME	4228657.0	4306769.0	4228894.0	<--BAD	4307006.0	<--BAD
SCUTSTCHECKWORD	58804.0	15468.0	58523.0	<--BAD	13059.0	<--BAD



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4.6 FUNC-SCU-04

Test Id:	FUNC-SCU-04
Initial Configuration:	DRCU_ON + AC/DC thermometry ON
Final Configuration:	DRCU_ON + AC/DC thermometry ON
Success Criteria:	<p>Test passed if PCALCURR/PCALV SCU HK parameters show the following values:</p> <ul style="list-style-type: none"> PCALCURR HK parameter which shows the measured PCAL current is ~ 0.1 mA. PCALV HK parameter which shows the measured PCAL voltage is ~ 0.02V

Test Procedure:

Step#	Action	Comments
1	Write the current value of PCALV and PCALCURR located in SCU_PARAMETERS display.	
2	Run FUNC-SCU-04 test procedure from the HCSS Test Procedure window on TOPE	
3	While the test is running Write the values of PCALV and PCALCURR.	
4	Contingency: If test fails repeat steps 1 to 3.	

Test Log:

Test Id	Key Parameter(s)	Expected Value Before/During test	Actual Value Before/After	Nb. of frames received	Test Result
FUNC-SCU-04	PCALCURR PCALV	0/0.1mA 0/0.02V	0 / 0.101 mA 0 / 0.0200 V	N/A	Success

Start time @: 12:48
End time @: 12: 48
OBSID: 0x30011A92
Comments:

Test Successful



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4.7 FUNC-SCU-05

Test Id:	FUNC-SCU-05
Initial Configuration:	DRCU_ON + AC/DC thermometry ON
Final Configuration:	DRCU_ON + AC/DC thermometry ON
Success Criteria:	Test passed if : <ul style="list-style-type: none"> • SCAL2CURR ,SCAL4CURR HK parameters which show the measured current read ~ 0.1 mA • SCAL2V,SCAL4V parameters which show the measured voltage read ~ 0.05V.

Test Procedure

Step#	Action	Comments
1	Write the current value of SCAL2V ,SCAL2CURR,SCAL4V,SCAL4CURR located in SCU_PARAMETERS display.	
2	Run FUNC-SCU-05 test procedure from the HCSS Test Procedure window on TOPE	
3	While the test is running write the values of SCAL2V ,SCAL2CURR,SCAL4V,SCAL4CURR.	
4	Contingency: If test fails repeat steps 1 to 3.	

Test Log:

Test Id	Key Parameter(s)	Expected Value Before/During test	Actual Value Before/After	Nb. of frames received	Test Result
FUNC-SCU-05	SCAL4CURR SCAL4V SCAL2CURR SCAL2V	0/0.1mA 0/0.05V 0/0.1mA 0/0.05V	0 / 0.1017 mA 0 / 0.0508 V 0 / 0.1000 mA 0 / 0.0498 V	N/A	Success

Start time @: 12:49

End time @: 12: 52

OBSID:0x30011A93

Comments:

The same command (parameter 0x4e) should be sent to both SCAL2/4

Test Successful



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4.8 FUNC-SCU-07

Test Id:	FUNC-SCU-07		
Initial Configuration:	DRCU_ON + AC/DC thermometry ON		
Final Configuration:	DRCU_ON + AC/DC thermometry ON		
Success Criteria:	Test passed if during the execution of the test the following SCU HK parameters give correspondent readings of:		
	SCU HK parameter	RAW	Converted
	SPHSV	~12715	~323mV
	EVHSV	~12715	~323mV
	SPHTRV	~14390	~ 8 V

Test Procedure:

Step#	Action	Comments
1	Run FUNC-SCU-07 test procedure from the HCSS Test Procedure window on TOPE.	Pending
2	While the test is running Write the values of current values of SPHSV, EVHSV, SPHTRV located in SCU_PARAMETERS display. (RAW and CONVERTED)	
3	Contingency: If test fails repeat steps 1 and 2.	

Test Log:

Test Id	Key Parameter(s)	Expected Value Before/During test	Actual Value Before/After	Nb. of frames received	Test Result
FUNC-SCU-07	SPHSV EVHSV SPHTRV	0/ ~ 323 mV 0/ ~ 323 mV 0/ ~ 8 V	~ 0 mV / 324.21 mV ~ 0 mV / 325.27 mV ~ 0 V / 8.85 V	N/A	Success

Start time @: 12:53
End time @: 12:56
OBSID:0x30011A94

Comments:

Test Successful



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Step#	Action	Comments
0	Open MCU_PARAMETERS display on SCOS Alpha Numeric Displays.	

4.9 FUNC-MCU-01

Test Id:	FUNC-MCU-01
Initial Configuration:	DRCU_ON + AC/DC thermometry ON
Final Configuration:	DRCU_ON + AC/DC thermometry ON +MCU ON
Success Criteria:	Test passed if: <ol style="list-style-type: none"> 1. MCU boots. 2. MCU voltages show expected values. 3. MAC, SMEC and BSM board temperatures shows ambient temperature.

Test Procedure:

Step#	Action	Comments
1	Run FUNC-MCU-01 test procedure from the HCSS Test Procedure window on TOPE	
2	When procedure is finished Write the values of the MCU voltages.	
3	Contingency: If test fails repeat steps 1 and 2.	

Test Log:

Test Id	Key Parameter(s)	Expected Value Before/After	Actual Value Before/After	Nb. of frames received	Test Result
FUNC-MCU-01	MCUP5V MCUP15V MCUP14V MCUM14V MCUM15V MCUMACTEMP MCUSMECTEMP MCUBSMTEMP	N/A / ~ 5V N/A / ~15V N/A / ~ 14V N/A / ~ -14V N/A / ~ -15V N/A / ~ 300K N/A / ~ 300K N/A / ~ 300K	- / 5.00V - / 15.50V - / 14.12V - / -14.49 V - / -15.60 V - / 291.32K - / 295.60K - / 295.00K	N/A	Success



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Start time @: 12:56
End time @: 14:35
OBSID:0x30011A95

Comments:

SCUDCDCSTAT went from 0 to 4 as expected

DRCU Power Supply LCD reading = (I = 0.87 A)

Test Successful



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4.10 FUNC-MCU-02

Test Id:	FUNC-MCU-02																																			
Initial Configuration:	DRCU_ON + AC/DC thermometry ON +MCU ON																																			
Final Configuration:	DRCU_ON + AC/DC thermometry ON +MCU ON																																			
Success Criteria:	<p>Test passed if :</p> <ol style="list-style-type: none"> MCU produces each type of the frames requested and with the following characteristics. <table border="1"> <thead> <tr> <th>Frame</th> <th>APID</th> <th>Type</th> <th>Subtype</th> <th>SID</th> <th>FrameID</th> <th>Frame length</th> </tr> </thead> <tbody> <tr> <td>Eng.</td> <td>0x509</td> <td>21</td> <td>3</td> <td>0x814</td> <td>0x14</td> <td>0x15</td> </tr> <tr> <td>BSM</td> <td>0x509</td> <td>21</td> <td>1</td> <td>0x612</td> <td>0x12</td> <td>0xD</td> </tr> <tr> <td>SMEC</td> <td>0x509</td> <td>21</td> <td>1</td> <td>0x410</td> <td>0x10</td> <td>0xC</td> </tr> <tr> <td>BSM +SMEC</td> <td></td> <td></td> <td></td> <td></td> <td></td> <td></td> </tr> </tbody> </table> <ol style="list-style-type: none"> No events are generated during the different frames generation. 	Frame	APID	Type	Subtype	SID	FrameID	Frame length	Eng.	0x509	21	3	0x814	0x14	0x15	BSM	0x509	21	1	0x612	0x12	0xD	SMEC	0x509	21	1	0x410	0x10	0xC	BSM +SMEC						
Frame	APID	Type	Subtype	SID	FrameID	Frame length																														
Eng.	0x509	21	3	0x814	0x14	0x15																														
BSM	0x509	21	1	0x612	0x12	0xD																														
SMEC	0x509	21	1	0x410	0x10	0xC																														
BSM +SMEC																																				

Test Procedure:

Step#	Action	Comments
1	Write the current value of MCUFRAMECNT located in MCU_PARAMETERS display	
2	Run QLA script FUNC-MCU-02.py on QLA console.	
3	Run FUNC-MCU-02 test procedure from the HCSS Test Procedure window on TOPE	
4	When test is finished Write the current value of MCUFRAMECNT.	
5	Contingency: If test fails repeat steps 1 to 4.	

Test Log:

Test Id	Key Parameter(s)	Expected Value Before/After	Actual Value Before/After	Nb. of frames received	Test Result
FUNC-MCU-02	MCUFRAMECNT	0 / ~ 6600	0 / 6493		Success



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Start time @: 12:58
End time @: 13:01
OBSID:0x30011A96
Comments:

QLA produced the following file:

 MCUENG: OBSID = 30011A96, BBTYP E = 0x8901, APID = 0x509, SID = 0x814

Parameter	Initial	Final	Increment	Expect	Incre.	Packet Chars.
MCUFRAMECNT	0	609	609	609		Packet type = 0x15
TM5N	5	32	27	27		subtype = 0x3
FrameTime	16.4223	16.4225				Frame ID = 0x14 Frame Len = 0x15

STATISTICS ON TIME BETWEEN RECEPTION OF 2 CONSECUTIVE FRAMES:
 mean = 16.42260 ms
 sigma = 0.00115 ms

 BSM: OBSID = 30011A96, BBTYP E = 0x8903, APID = 0x509, SID = 0x612

Parameter	Initial	Final	Increment	Expect	Incre.	Packet Chars.
MCUFRAMECNT	609	1250	641	609		Packet type = 0x15
TM5N	32	49	17	17		subtype = 0x1
FrameTime	15.5809	15.5809				Frame ID = 0x12 Frame Len = 0xD

STATISTICS ON TIME BETWEEN RECEPTION OF 2 CONSECUTIVE FRAMES:
 mean = 15.58042 ms
 sigma = 0.00104 ms

 SMEC: OBSID = 30011A96, BBTYP E = 0x8902, APID = 0x509, SID = 0x410

Parameter	Initial	Final	Increment	Expect	Incre.	Packet Chars.
MCUFRAMECNT	1250	3624	2374	2375		Packet type = 0x15
TM5N	49	107	58	58		subtype = 0x1
FrameTime	4.2112	4.2114				Frame ID = 0x10 Frame Len = 0xC

STATISTICS ON TIME BETWEEN RECEPTION OF 2 CONSECUTIVE FRAMES:
 mean = 4.21092 ms
 sigma = 0.00090 ms

 SMEC+BSM: OBSID = 30011A96, BBTYP E = 0x8904, APID = 0x509, SID = 0x612

Parameter	Initial	Final	Increment	Expect	Incre.	Packet Chars.
MCUFRAMECNT	3624	6493	2869	2850		Packet type = 0x15
TM5N	107	178	71	71		subtype = 0x1
FrameTime SMEC	4.2112	4.2112				Frame ID = 0x10, Len = 0xC
FrameTime BSM	20.2143	20.2143				Frame ID = 0x12, Len = 0xD

STATISTICS ON TIME BETWEEN RECEPTION OF 2 CONSECUTIVE FRAMES:
 mean = 4.21093 ms (SMEC), 20.21245 ms (BSM)
 sigma = 0.00090 ms (SMEC), 0.00157 ms (BSM)



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4.11 FUNC-MCU-03

Test Id:	FUNC-MCU-03																																			
Initial Configuration:	DRCU_ON + AC/DC thermometry ON +MCU ON																																			
Final Configuration:	DRCU_ON + AC/DC thermometry ON +MCU ON																																			
Success Criteria:	<p>Test passed if :</p> <ol style="list-style-type: none"> MCU produces 99 frames of each type of frames requested with the following characteristics: <table border="1"> <thead> <tr> <th>Frame</th> <th>APID</th> <th>Type</th> <th>Subtype</th> <th>SID</th> <th>FrameID</th> <th>Frame length</th> </tr> </thead> <tbody> <tr> <td>Eng.</td> <td>0x508</td> <td>21</td> <td>3</td> <td>0x814</td> <td>0x14</td> <td>0x15</td> </tr> <tr> <td>BSM</td> <td>0x508</td> <td>21</td> <td>1</td> <td>0x612</td> <td>0x12</td> <td>0xD</td> </tr> <tr> <td>SMEC</td> <td>0x508</td> <td>21</td> <td>1</td> <td>0x410</td> <td>0x10</td> <td>0xC</td> </tr> <tr> <td>BSM +SMEC</td> <td></td> <td></td> <td></td> <td></td> <td></td> <td></td> </tr> </tbody> </table> <ol style="list-style-type: none"> No events are generated during the different frames generation. QLA analysis results are correct. <p>QLA to give go ahead.</p>	Frame	APID	Type	Subtype	SID	FrameID	Frame length	Eng.	0x508	21	3	0x814	0x14	0x15	BSM	0x508	21	1	0x612	0x12	0xD	SMEC	0x508	21	1	0x410	0x10	0xC	BSM +SMEC						
Frame	APID	Type	Subtype	SID	FrameID	Frame length																														
Eng.	0x508	21	3	0x814	0x14	0x15																														
BSM	0x508	21	1	0x612	0x12	0xD																														
SMEC	0x508	21	1	0x410	0x10	0xC																														
BSM +SMEC																																				

Test Procedure:

Step#	Action	Comments
1	Write the current value of MCUFRAMECNT located MCU_PARAMETERS display.	
2	Run QLA script FUNC-MCU-03.py on QLA console.	
3	Run FUNC-MCU-03 test procedure from the HCSS Test Procedure window on TOPE	
4	When test is finished Write the current value of MCUFRAMECNT	
5	Contingency: If test fails repeat steps 1 to 4.	

Test Log:

Test Id	Key Parameter(s)	Expected Value Before/After	Actual Value Before/After	Nb. of frames received	Test Result
FUNC-MCU-03	MCUFRAMECNT	n/ n+297 n~6600	6493 / 6790		Success



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**Start time @: 13:01
End time @: 13:03
OBSID:0x30011A97**



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4.12 FUNC-MCU-04

Test Id:	FUNC-MCU-04														
Initial Configuration:	DRCU_ON + AC/DC thermometry ON +MCU ON														
Final Configuration:	DRCU_ON + AC/DC thermometry ON +MCU ON														
Success Criteria:	<p>Test passed if:</p> <ol style="list-style-type: none"> MCU produces 100 frames of Test Pattern with the following characteristics: <table border="1"> <thead> <tr> <th>Frame</th> <th>APID</th> <th>Type</th> <th>Subtype</th> <th>SID</th> <th>FrameID</th> <th>Frame length</th> </tr> </thead> <tbody> <tr> <td>Test</td> <td>0x509</td> <td>21</td> <td>3</td> <td>0x915</td> <td>0x15</td> <td>0x15</td> </tr> </tbody> </table> <ol style="list-style-type: none"> MCU Test pattern produced is the same as the previous time this test was run. <p>QLA to give go ahead.</p>	Frame	APID	Type	Subtype	SID	FrameID	Frame length	Test	0x509	21	3	0x915	0x15	0x15
Frame	APID	Type	Subtype	SID	FrameID	Frame length									
Test	0x509	21	3	0x915	0x15	0x15									

Test Procedure:

Step#	Action	Comments
1	Write the current value of MCUFRAMECNT located in MCU_PARAMETERS display.	
2	Run QLA script FUNC-MCU-04.py on QLA console.	
3	On Lincoln run FUNC-MCU-04 test procedure from the HCSS Test Procedure window on TOPE	
4	When test is finished Write the current value of MCUFRAMECNT	
5	Contingency: If test fails repeat steps 1 to 4.	

Test Log:

Test Id	Key Parameter(s)	Expected Value Before/After	Actual Value Before/After	Nb. of frames received	Test Result
FUNC-MCU-04	MCUFRAMECNT	m/ m+99 m~6600	6790/ 6889		Success



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Start time @: 13:03
End time @: 13:04
OBSID: 0x30011A98

Comments:

QLA produced the following file:

MCU Test Pattern @ Fri Jan 26 13:03:37 GMT 2007
..compared with data from MCU Test Pattern @ Thu Jan 25 14:47:41 GMT 2007, OBSID=0x30011A5F

Name	New Value[0]	New Value[20]	Comp Value[0]		Comp Value[20]	
MCUTSTBBID	2.298806273E9	0.0	2.298806273E9	--> OK	0.0	--> OK
MCUTSTBLKLEN	21.0	21.0	21.0	--> OK	21.0	--> OK
MCUTSTFRAMEID	21.0	21.0	21.0	--> OK	21.0	--> OK
MCUTST001	21845.0	21845.0	21845.0	--> OK	21845.0	--> OK
MCUTST002	43690.0	43690.0	43690.0	--> OK	43690.0	--> OK
MCUTST003	21844.0	21844.0	21844.0	--> OK	21844.0	--> OK
MCUTST004	43688.0	43688.0	43688.0	--> OK	43688.0	--> OK
MCUTST005	21840.0	21840.0	21840.0	--> OK	21840.0	--> OK
MCUTST006	43680.0	43680.0	43680.0	--> OK	43680.0	--> OK
MCUTST007	21825.0	21825.0	21825.0	--> OK	21825.0	--> OK
MCUTST008	43650.0	43650.0	43650.0	--> OK	43650.0	--> OK
MCUTST009	21765.0	21765.0	21765.0	--> OK	21765.0	--> OK
MCUTST010	43530.0	43530.0	43530.0	--> OK	43530.0	--> OK
MCUTST011	21524.0	21524.0	21524.0	--> OK	21524.0	--> OK
MCUTST012	43048.0	43048.0	43048.0	--> OK	43048.0	--> OK
MCUTST013	20560.0	20560.0	20560.0	--> OK	20560.0	--> OK
MCUTST014	41120.0	41120.0	41120.0	--> OK	41120.0	--> OK



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Step#	Action	Comments
0	Open CHOP PARAMETERS display on SCOS Alpha Numeric Displays.	

4.13 FUNC-BSM-01

Test Id:	FUNC-BSM-01
Initial Configuration:	DRCU_ON + AC/DC thermometry ON +MCU ON
Final Configuration:	DRCU_ON + AC/DC thermometry ON +MCU ON + BSM ON (open loop)
Success Criteria:	Test passed if: <ol style="list-style-type: none"> 1. CHOPSENSPWR HK parameter goes from 0 to 1 2. CHOPDACVAL HK parameter goes from 0 to 0x8000 3. CHOPSENSIG HK parameter shows variation from off to on 4. JIGGSENSPWR HK parameter goes from 0 to 1 5. JIGGDACVAL parameter goes from 0 to 0x8000 6. JIGGSENSSIG HK parameter shows variation from off to on

Test Procedure

Step#	Action	Comments
1	On QLA bring up a time series display of the following HK parameters: CHOPSENSPWR CHOPDACVAL CHOPSENSIG JIGGSENSPWR JIGGDACVAL JIGGSENSSIG	
2	Run FUNC-BSM-01 test procedure from the HCSS Test Procedure window on TOPE	
3	When the test is finished record all the Key parameters noted bellow	
	Contingency: If test fails repeat steps 1 and 2.	

Test Log:

Test Id	Key Parameter(s)	Expected Value Before/After	Actual Value Before/After	Nb. of frames received	Test Result
FUNC-BSM-01	CHOPSENSPWR CHOPLOOPMODE CHOPDACVAL CHOPFFGAIN CHOPSENSSIG JIGGSENSPWR JIGGLOOPMODE JIGGDACVAL JIGGFFGAIN JIGGSENSSIG	0/1 3/3 0x8000/0x8000 0xBEB/0xBEB ~0x8000/? 0/1 3/3 0x8000/0x8000 0xBEB/0xBEB ~0x8000/?	0/1 3/3 0x8000/0x8000 0xBEB/0x770 0x7FFD/0x94B2 0/1 3/3 0x8000/0x8000 0xBEB/0xF6E 0x7FF2/~ 0x8CB6	N/A	Success



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Start time @: 14:39
End time @: 14:40
OBSID: 0x30011A99
Comments:

The BSM was switched ON correctly. The highlighted Chop and Jiggle FF gains are consistent with the latest BSMNominalSettings.txt table in the CUS.



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4.14 FUNC-BSM-02c

Test Id:	FUNC-BSM-02c
Initial Configuration:	DRCU_ON + AC/DC thermometry ON +MCU ON + BSM ON (open loop)
Final Configuration:	DRCU_ON + AC/DC thermometry ON +MCU ON + BSM ON (open loop)
Success Criteria:	Test passed if the chop sensor signal evolves in the same way as the positions set.(i.e if (pos1 > pos2 → sig1 > sig2)

Test Procedure:

Step#	Action	Comments
1	On QLA open up a time series display of HK parameter CHOPDACVAL and CHOPSENSSIG	
2	Run FUNC-BSM-02c test procedure from the HCSS Test Procedure window on TOPE	
3	Contingency: If test fails repeat steps 1.	

Test Log:

Test Id	Key Parameter(s)	Expected Value Before/After	Actual Value Before/After	Nb. of frames received	Test Result
FUNC-BSM-02c	CHOPDACVAL CHOPSENSSIG		See below	N/A	Success

**Start time @: 14:42
End time @: 14:43
OBSID: 0x30011A9A**

Comments:

The BSM moved along the chop axis in the same direction as expected.

Insert QLA picture

4.15 FUNC-BSM-02j

Test Id:	FUNC-BSM-02j
Initial Configuration:	DRCU_ON + AC/DC thermometry ON +MCU ON + BSM ON (open loop)
Final Configuration:	DRCU_ON + AC/DC thermometry ON +MCU ON + BSM ON (open loop)
Success Criteria:	Test passed if the jiggle sensor signal evolves in the same way as the



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	positions set.(i.e if (pos1 > pos2 → sig1 > sig2)
--	---

Test Procedure:

Step#	Action	Comments
1	On QLA open up a time series display of HK parameter JIGGDACVAL and JIGGSENSSIG	
2	Run FUNC-BSM-02j test procedure from the HCSS Test Procedure window on TOPE	
3	Contingency: If test fails repeat steps 1.	

Test Log:

Test Id	Key Parameter(s)	Expected Value Before/After	Actual Value Before/After	Nb. of frames received	Test Result
FUNC-BSM-02j	JIGGDACVAL JIGGSENSSIG		See below	N/A	Success

Start time @: 14:44
End time @: 14:46
OBSID: 0x30011A9B
Comments:

The BSM moved along the jiggle axis in the same direction as expected.

Insert QLA picture





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4.16 FUNC-BSM-03

Test Id:	FUNC-BSM-03
Initial Configuration:	DRCU_ON + AC/DC thermometry ON +MCU ON + BSM ON (open loop)
Final Configuration:	DRCU_ON + AC/DC thermometry ON +MCU ON + BSM ON (open loop)
Success Criteria:	<p>Test passed if the chop sensor signal evolves in the same way as the positions set.(i.e if (pos1 > pos2 → sig1 > sig2) for each jiggle position.</p> <p>Note: During warm tests the voltages on both chop and jiggle motors are likely to be saturated (CHOP/JIGGMOTORVOLT RAW values of ~ 0xFFFF) due to the high resistance of the motor coil at ambient temperature.</p>

Test Procedure

Step#	Action	Comments
1	On QLA open up a time series display of HK parameters: CHOPPOSN CHOPDACVAL CHOPMOTORCURRE CHOPSENSSIG CHOPMOTORVOLT JIGGPOSN JIGGDACVAL JIGGMOTORCURRE JIGGSENSSIG JIGGMOTORVOLT	
2	Run FUNC-BSM-03 test procedure from the HCSS Test Procedure window on TOPE	
3	Contingency: If test fails repeat step 2.	

Test Log:

Test Id	Key Parameter(s)	Expected Value Before/After	Actual Value Before/After	Nb. of frames received	Test Result
FUNC-BSM-03				N/A	Success



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Start time @: 14:48
End time @: 14: 52
OBSID:0x30011A9C

Comments:

Ran TOPE script with input parameters:

Jiggle Start = 0x4000

Jiggle End = 0xC000

Jiggle Step = 0x4000

Chop Start = 0x3000

Chop End = 0xF000

Chop Step = 0x1000

3 seconds per step

Insert QLA picture

Jiggle position as given by senssig shows going to position then coming back as the chop position is stepped. This is due to the coupling between the axis.

Insert QLA picture



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4.17 FUNC-BSM-06

Step#	Action	Comments
0	Execute BSM_INIT from HCSS Test Procedures	Started at 16:52 OBSID: 0x30011A9D

4.18

Test Id:	FUNC-BSM-06
Initial Configuration:	DRCU_ON + AC/DC thermometry ON +MCU ON + BSM ON (open loop)
Final Configuration:	DRCU_ON + AC/DC thermometry ON +MCU ON + BSM ON (open loop)
Success Criteria:	<p>Note: The purpose of this test is to check the correctness of the BSM close loop initialisation procedure and the default PID parameters</p> <p>If the dynamical behaviour of the BSM during chopping with these PID parameters is close or within requirements this indicates that the PID parameters used can be applied to cold testing with certain adjustment. If NOT these indicates that the PID parameters need further tuning BUT NOT TO BE DONE DURING THESE TEST.</p> <p>In any case the success/fail criteria are NOT applicable for this test.</p>

Test Procedure

Step#	Action	Comments
1	On QLA open up a time series display of HK parameters: BSMCHOPSENSSIG BSMCHOPMOTORCURRE BSMCHOPMOTORVOLT BSMJIGGSENSSIG BSMJIGGMOTORCURRE BSMJIGGMOTORVOLT	
2	Run FUNC-BSM-06 test procedure from the HCSS Test Procedure window on TOPE	
3	Contingency: None contemplated.	

Test Log:

Test Id	Key Parameter(s)	Expected Value Before/After	Actual Value Before/After	Nb. of frames received	Test Result
FUNC-BSM-06	CHOPSENSSIG CHOPMOTORCURRE CHOPDACVAL	??/ ??/ ??/		N/A	N/A

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Start time @: 14:56
End time @: 15:02
OBSID:0x30011AA0

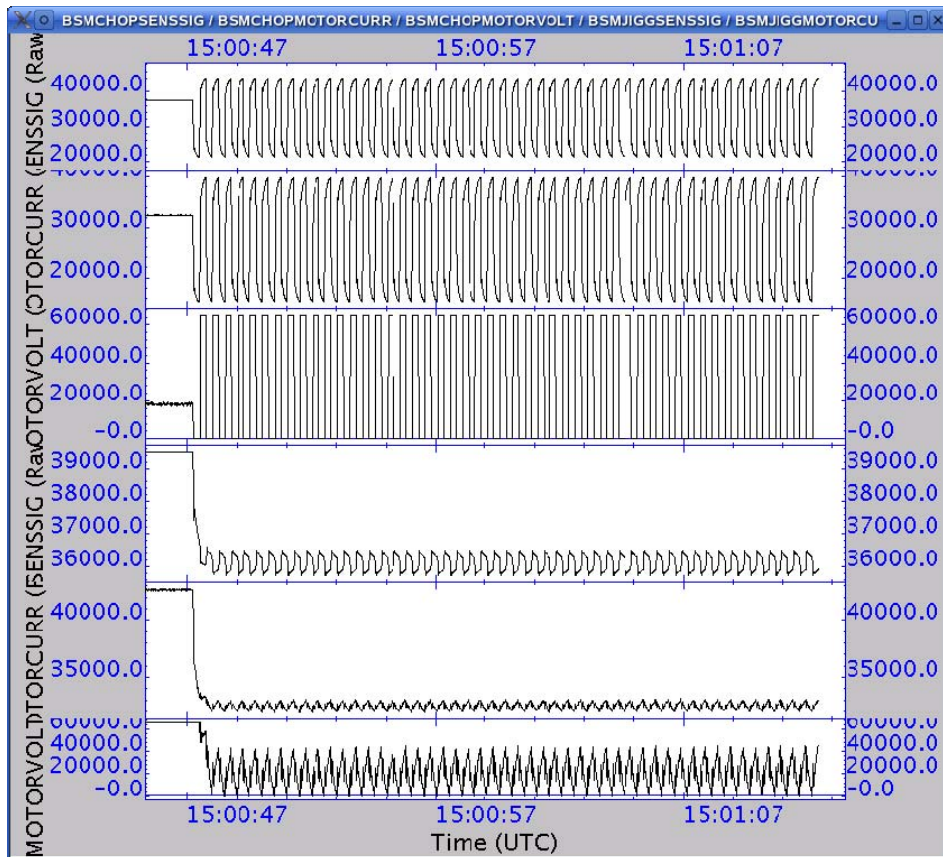
Comments:

Ran TOPE script with default values that the input parameters have:

Input Parameter	Value
Frame rate	125 Hz
On source chop	0x5279
On source jiggle	0x8D00
Off source chop	0xAD87
Off source chop	0x8D00
Number of cycles	50
Chop cycle period	500000 (us)
DCU frame type	0
Number of DCU frame per half cycle	4
DCU delay to start sampling	34959 (us)
Number of BSM samples	65535 = continuous sampling

Had to run LoadCommandList procedure from TOPE as apparently the BSM CHOP command list had not been uploaded correctly due to the initial CDMS Sim Bus problem.
Repeated the functional test then the BSM chopped.

Second Attempt behaviour:



Note: Although both sensor signals show clear signs of not correct PID settings and the jiggle motor current is very irregular the purpose of this test is to prove that we can operate the BSM in its nominal operational mode PID chopping.



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Step#	Action	Comments
4	Execute BSM_OFF from HCSS Test Procedures	Switched OFF the BSM @ 15:08 Obsid: 0x30011AA1

Manually set the MODE HK parameter to REDY: SET_OBS_MODE(0x200)



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4.19 FUNC-SMEC-03

Test Id:	FUNC-SMEC-03
Initial Configuration:	DRCU_ON + AC/DC thermometry ON +MCU ON+ SMEC ON (open loop)
Final Configuration:	DRCU_ON + AC/DC thermometry ON +MCU ON+ SMEC ON (open loop)
Success Criteria:	Test passed if: SMEC encoder signals 1 and 2 show a variation on their amplitudes from one LED illumination level to another.

Test Procedure:

Step#	Action	Comments
1	On QLA bring up a time series display of the following Nominal HK parameters: SMECENC SIGAMP1 SMECENC SIGAMP2	
2	Run FUNC-SMEC-03 test procedure from the HCSS Test Procedure window on TOPE	
3	Contingency: If test fails repeat steps 1 and 2.	

Test Log:

Test Id	Key Parameter(s)	Expected Value Before/After	Actual Value Before/After	Nb. of frames received	Test Result
FUNC-SMEC-03	SMECENC SIG1 SMECENC SIG2				Success



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Start time @: 15:12
End time @: 15:13
OBSID: 0x30011AA2

Comments:

Using input parameters:

Start level = 3

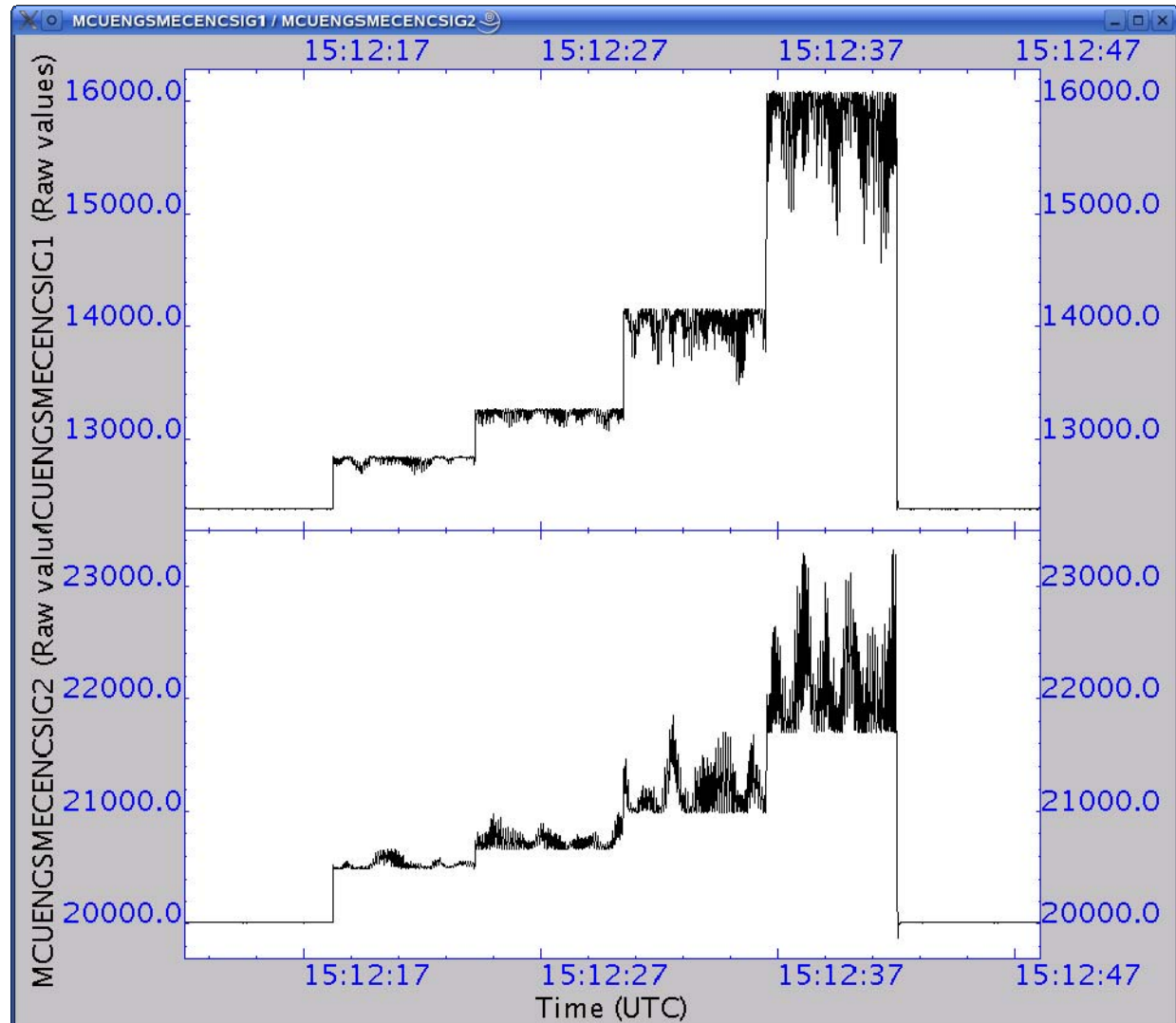
End level = 6

Step level = 1

5 seconds at each

Also plotted SMECENCPWR.

The level of the encoder signals 1 and 2 changed as the level of the power changed staying in range throughout the sequence.



Note: Procedure should be change to plot the QLA MCU ENG frames rather than the HK values which have a much lower resolution.



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4.20 FUNC-SMEC-01

Test Id:	FUNC-SMEC-01
Initial Configuration:	DRCU_ON + AC/DC thermometry ON +MCU ON+ SMEC ON (open loop)
Final Configuration:	DRCU_ON + AC/DC thermometry ON +MCU ON+ SMEC ON (open loop)
Success Criteria:	Test passed if : <ol style="list-style-type: none"> 1. SMECENCPWR HK parameter changes from 0 to 6. 2. SMEC encoder signals 1 and 2 amplitude show variation when encoder is switched ON. 3. SMEC LVDT is switched ON. 4. SMEC LVDT DC and AC signals show variation when LVDT is switched ON.

Test Procedure:

Step#	Action	Comments
0	Open SMEC PARAMETERS display on SCOS Alpha Numeric Displays.	
1	On QLA bring up a display of the following HK parameters: SMECENCPWR SMECENC SIG1AMP SMECENC SIG2AMP SMECLVDTDCSIG SMECLVDTACSIG	
2	Run FUNC-SMEC-01 test procedure from the HCSS Test Procedure window on TOPE	
	Contingency: If test fails repeat steps 1.	

Test Log:

Test Id	Key Parameter(s)	Expected Value Before/ After	Actual Value Before/After	Nb. of frames received	Test Result
FUNC-SMEC-01	SMECENCPWR SMECLVDPWR SMECENC SIG1 SMECENC SIG1AMP SMECENC SIG1OFF SMECENC SIG2 SMECENC SIG2AMP SMECENC SIG2OFF		0/6 0/1 not relevant/~ 0x3C00 0xCE20/0xDEA8 not relevant/~0x5400 0xCE20/0xAFC8	N/A	



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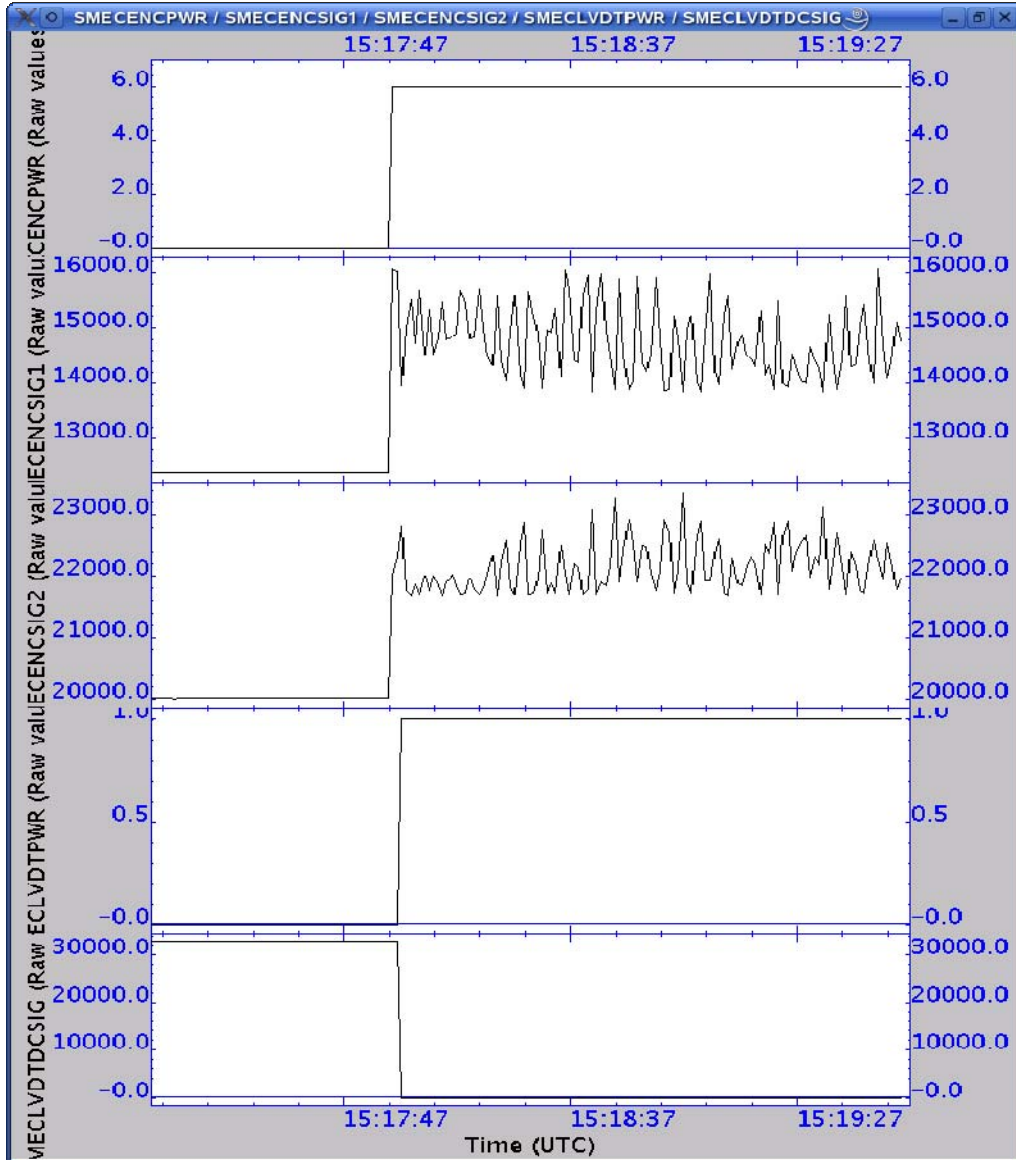
Start time @: 15:17

End time @: 15:18

OBSID: 0x30011AA2

Comments:

Procedure still asks from encoder signal amplitudes when it should only ask for encoder signals





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4.21 FUNC-SMEC-04a

Test Id:	FUNC-SMEC-04a
Initial Configuration:	DRCU_ON + AC/DC thermometry ON+MCU ON+ SMEC ON (open loop) UNLATCHED
Final Configuration:	DRCU_ON + AC/DC thermometry ON+MCU ON+ SMEC ON (open loop) UNLATCHED
Success Criteria:	Test passed if only the SMECMOTORCURR shows a variation meaning that the mechanism has not moved.

Test Procedure:

Step#	Action	Comments
1	On QLA bring up a time series display of the following Nominal HK parameters: SMECENC SIG1 SMECENC SIG2 SMECLVDTDCSIG SMECLVDTACSIG SMECMOTORCURR	
2	Run FUNC-SMEC-04a test procedure from the HCSS Test Procedure window on TOPE	
3	Contingency: If test fails repeat steps 1.	

Test Log:

Test Id	Key Parameter(s)	Expected Value Before/After	Actual Value Before/After	Nb. of frames received	Test Result
FUNC-SMEC-04a	SMECLVDTDCSIG		13A4/		



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Start time @: 15:30

End time @: 15:33

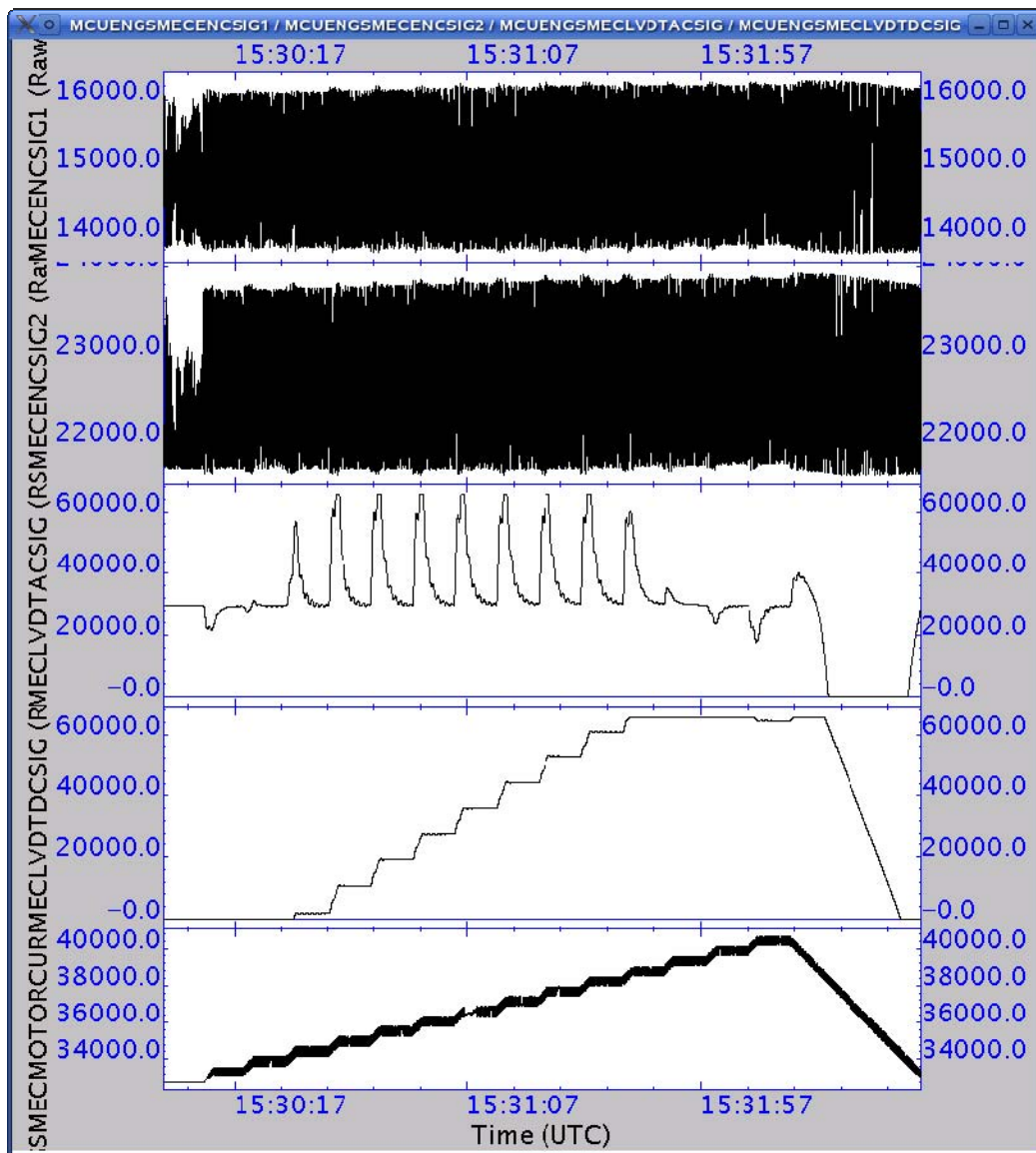
OBSID:0x30011AA3

Comments:

Used the following input parameters to the TOPE script:

- Scan Start = 1000 um
- Scan End = 15000 um
- Scan Step = 1000 um
- Scan F speed = 500 um/s
- Scan R speed = 1000 um/s
- Time at each position = 5 s

The test procedure specifies HK parameters should be displayed when the SMEC science parameters are needed.





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4.22 FUNC-SMEC-02A/B

Test Id:	FUNC-SMEC-02A/B
Initial Configuration:	DRCU_ON + AC/DC thermometry ON +MCU ON + SMEC ON If WFT prior to cooldown : Smec Latched If WFT after warm up : Smec Unlatched
Final Configuration:	DRCU_ON + AC/DC thermometry ON +MCU ON + SMEC ON If WFT prior to cooldown : Smec Unlatched If WFT after warm up : Smec Latched
Success Criteria:	Test passed if : Prior to un-latching the resistance across pins 7 and 8 of the launch latch is ~ 368 Ohms. After un-latching the resistance is 483 Ohms. Note: These resistance values were recorded for the CQM SMEC model, for the flight SMEC, these values are expected to vary.

Step#	Action	Comments
1	Measure the resistance across pins 7 and 8 of the launch latch.	This step is not applicable anymore
2	If WFT prior to cooldown: Run FUNC-SMEC-02A test procedure from the HCSS Test Procedure window on TOPE If WFT after warm up: Run FUNC-SMEC-02B test procedure from the HCSS Test Procedure window on TOPE	
3	Measure the resistance across pins 7 and 8 of the launch latch.	
4	Contingency: If test fails repeat steps 1.	

Test Id	Key Parameter(s)	Expected Value Before/After	Actual Value Before/After	Nb. of frames received	Test Result
FUNC-SMEC-02A/B				N/A	Passed

Start time:
End time :
OBSID:
Test not performed as the SMEC is already unlatched and will be left unlatched for the cooldown.



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4.23 FUNC-SMEC-09

Test Id:	FUNC-SMEC-09
Test Purpose:	SMEC Open Loop Scan Test.
Initial Configuration:	DRCU_ON + AC/DC thermometry ON+MCU ON+ SMEC ON (open loop)
Final Configuration:	DRCU_ON + AC/DC thermometry ON+MCU ON+ SMEC ON (open loop)
Success Criteria:	Test passed if SMECLVDTDCSIG parameter shows a variation according to the different position of the SMEC along the scan.

Test Procedure:

Step#	Action
1	On QLA bring up a time series display of the following SMEC nominal science parameters: SMECENC SIG1 SMECENC SIG2 SMECLVDTDCSIG SMECLVDTAC SIG SMECMOTORCURR
2	Run FUNC-SMEC-09 test procedure from the HCSS Test Procedure window on TOPE
3	Contingency: If test fails repeat steps 1.

Test Log:

Test Id	Key Parameter(s)	Expected Value Before/After	Actual Value Before/After	No. of frames received	Test Result
FUNC-SMEC-09	All above mentioned in step 2	N/A	N/A	N/A	Success



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Start time @: 16:08
End time @: 16:20
OBSID: 0x30011AA5
Comments:

ALL SMEC FUNCTIONAL TESTS PRODUCE ENGINEERING FRAMES NOT SMEC SCIENCE AND THIS SHOULD BE NOTED IN THE PROCEDURES

Manually set the encoder signal 1/2 offsets to :
SMECEMCSIGOFF1 = 14500 (0x38A4)
SMECEMCSIGOFF2 = 22500 (0x57E4)
as the SMEC_ON script still does not incorporate a PRIME/REDUNDANT switch

Start point = 1 mm,
End point = 38 mm
Forward speed = 0.5 mm/s
Reverse speed = 0.5 mm/s
Number of scan = 4

Encoder not counting

Reset manually
SMECEMCSIGOFF1 = 15000
SMECEMCSIGOFF2 = 23000

Repeated SCAN: OBSID: 0x30011AA6

Start point = 1 mm,
End point = 15 mm
Forward speed = 0.2 mm/s
Reverse speed = 0.2 mm/s
Number of scan = 2

Encoder now counting

See next test for a comparison with the open to close loop performance



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Step#	Action	Comments
0	Execute SMEC_INIT from HCSS Test Procedures	Obsid: 0x30011AA7

4.24 FUNC-SMEC-07

Test Id:	FUNC-SMEC-07
Test Purpose:	SMEC Close Loop Scan Test.
Initial Configuration:	DRCU_ON + AC/DC thermometry ON+MCU ON+ SMEC ON (close loop)
Final Configuration:	DRCU_ON + AC/DC thermometry ON+MCU ON+ SMEC ON (close loop)
Success Criteria:	Test passed if: SMECENCPOS HK parameter shows identical values as those of the SMECTRAJPOSN HK parameter during the scan.

Test Procedure:

Step#	Action
1	On QLA bring up a time series display of the following SMEC nominal science parameters: SMECENC SIG1 SMECENC SIG2 SMECLVDTDCSIG SMECLVDTACSIG SMECMOTORCURR
2	Run FUNC-SMEC-07 test procedure from the HCSS Test Procedure window on TOPE
3	Contingency: If test fails repeat steps 1.

Test Log:

Test Id	Key Parameter(s)	Expected Value Before/After	Actual Value Before/After	No. of frames received	Test Result
FUNC-SMEC-07	All above mentioned in step 1	N/A	N/A	N/A	Success



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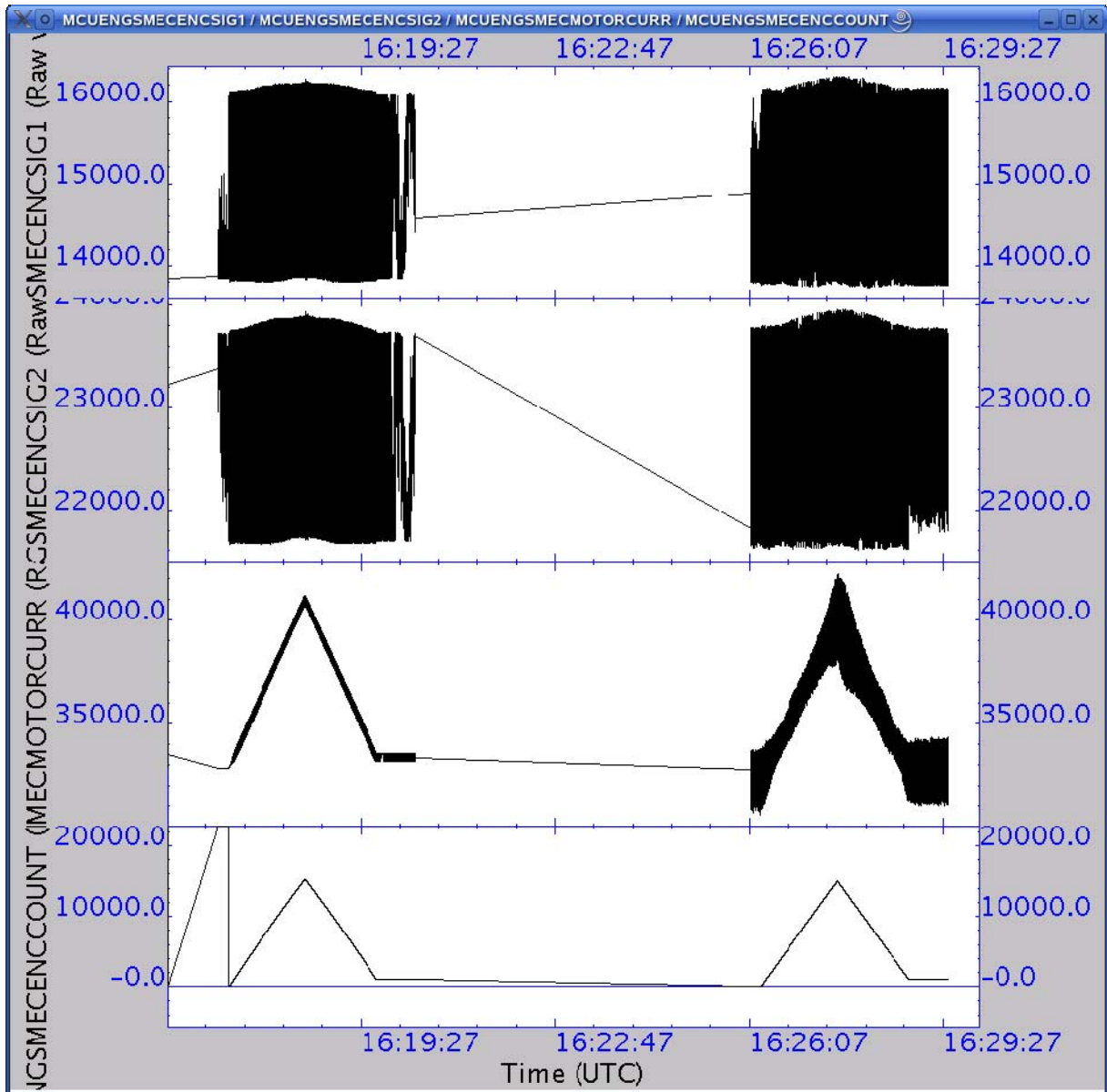
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Start time @: 16:26
End time @: 16:30
OBSID: 0x30011AA8
Comments:

Start point = 1 mm,
End point = 15 mm
Forward speed = 0.2 mm/s
Reverse speed = 0.2 mm/s
Number of scan = 2

The loop remained closed through out the scan but note the much larger scatter on the SMEC motor current during the close loop scan which most probably indicates a wrong set of PID parameters for redundant SMEC warm operation. Nevertheless this test proves that the redundant SMEC CAN be operated in close loop.





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4.25 FUNC-SMEC-04B

Test Id:	FUNC-SMEC-04B
Test Purpose:	SMEC Close Loop Position Test. SMEC close loop operation check.
Initial Configuration:	DRCU_ON + AC/DC thermometry ON+MCU ON+ SMEC ON (open loop)
Final Configuration:	DRCU_ON + AC/DC thermometry ON+MCU ON+ SMEC ON (open loop)
Success Criteria:	Test passed if : SMECENCPOS HK parameter shows identical values as those of the SMECTRAJPOSN HK parameter for the different commanded SMEC positions.(1mm to 25mm in steps of 1mm)

Test Procedure:

Step#	Action
1	On QLA bring up 2 time series displays: Display 1 of the following MCU Engineering block parameters: MCUENGSMECENC SIG1 MCUENGSMECENC SIG2 MCUENGSMECLVDTDCSIG MCUENGSMECLVDTAC SIG MCUENGSMECMOTORCURR Display 1 of the following SMEC HK parameters: SMECENCPOSN SMECTRAJPOSN
2	Run FUNC-SMEC-04B test procedure from the HCSS Test Procedure window on TOPE
3	Contingency: If test fails repeat steps 1.

Test Log:

Test Id	Key Parameter(s)	Expected Value Before/After	Actual Value Before/After	No. of frames received	Test Result
FUNC-SMEC-04B	All above mentioned in step 1	N/A	N/A	N/A	Not done
Start time @: 16:37 End time @: 16:41 OBSID: 0x30011AA9 Comments: Start point = 1 mm End point = 15 mm Steps = 1 mm Forward speed = 0.5 mm/s Reverse speed = 1.0 mm/s					



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Step#	Action	Comments
4	Execute SMEC_OFF from HCSS Test Procedures	Done at 16:49; Obsid:0x30011AAA



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Step#	Action	Comments
0	Open DCU PARAMETERS SCOS Alpha Numeric Display	

4.26 FUNC-DCU-01

Test Id:	FUNC-DCU-01																																																																
Initial Configuration:	DRCU_ON + AC/DC thermometry ON+MCU ON																																																																
Final Configuration:	DRCU_ON + AC/DC thermometry ON+MCU ON																																																																
Success Criteria:	<p>Test passed if:</p> <ol style="list-style-type: none"> DCU produces each type of DCU nominal science frame with the following characteristics. <table border="1"> <thead> <tr> <th>APID</th> <th>Type</th> <th>S.type</th> <th>SID</th> <th>Frame ID</th> <th>Frame type</th> <th>Nb. Of frames</th> <th>Nb. of pkts.</th> </tr> </thead> <tbody> <tr> <td>0x505</td> <td>21</td> <td>1</td> <td>0x200</td> <td>0</td> <td>PF</td> <td>100</td> <td>100</td> </tr> <tr> <td>0x507</td> <td>21</td> <td>1</td> <td>0x201</td> <td>1</td> <td>SF</td> <td>100</td> <td>17</td> </tr> <tr> <td>0x505</td> <td>21</td> <td>2</td> <td>0x102</td> <td>2</td> <td>PSW</td> <td>100</td> <td>34</td> </tr> <tr> <td>0x505</td> <td>21</td> <td>2</td> <td>0x103</td> <td>3</td> <td>PMW</td> <td>100</td> <td>25</td> </tr> <tr> <td>0x505</td> <td>21</td> <td>2</td> <td>0x104</td> <td>4</td> <td>PLW</td> <td>100</td> <td>12</td> </tr> <tr> <td>0x507</td> <td>21</td> <td>2</td> <td>0x105</td> <td>5</td> <td>SSW</td> <td>100</td> <td>12</td> </tr> <tr> <td>0x507</td> <td>21</td> <td>2</td> <td>0x106</td> <td>6</td> <td>SLW</td> <td>100</td> <td>7</td> </tr> </tbody> </table> <ol style="list-style-type: none"> The frame time difference between consecutive DCU frames of each type corresponds to the sampling rate. Photometer Sampling rate is 15.3Hz → Δt ~ 65.5 ms Spectrometer Sampling rate is 80Hz → Δt = 12.5 ms The SPIRE HK parameter DCUFRAMECNT increments by 700. No events are generated during the frames generation. 	APID	Type	S.type	SID	Frame ID	Frame type	Nb. Of frames	Nb. of pkts.	0x505	21	1	0x200	0	PF	100	100	0x507	21	1	0x201	1	SF	100	17	0x505	21	2	0x102	2	PSW	100	34	0x505	21	2	0x103	3	PMW	100	25	0x505	21	2	0x104	4	PLW	100	12	0x507	21	2	0x105	5	SSW	100	12	0x507	21	2	0x106	6	SLW	100	7
APID	Type	S.type	SID	Frame ID	Frame type	Nb. Of frames	Nb. of pkts.																																																										
0x505	21	1	0x200	0	PF	100	100																																																										
0x507	21	1	0x201	1	SF	100	17																																																										
0x505	21	2	0x102	2	PSW	100	34																																																										
0x505	21	2	0x103	3	PMW	100	25																																																										
0x505	21	2	0x104	4	PLW	100	12																																																										
0x507	21	2	0x105	5	SSW	100	12																																																										
0x507	21	2	0x106	6	SLW	100	7																																																										

Test Procedure:

Step#	Action	Comments
1	Write the current value of DCUFRAMECNT located d in DCU PARAMETERS AND	
2	Run FUNC-DCU-01 test procedure from the HCSS Test Procedure window on TOPE	
3	Write the current value of DCUFRAMECNT located d in DCU PARAMETERS AND	
4	Contingency:	



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If test fails repeat steps 1 to 3.

Test Log:

Test Id	Key Parameter(s)	Expected Value Before/After	Actual Value Before/After	Nb. of frames received	Test Result
FUNC-DCU-01	DCUFRAMECNT	n/n+700 n depends on the BSM chop operations on FUNC-BSM-06	0 / 700	700	

Start time @: 29/01/2007 - 14:19

End time @: 29/01/2007 - 14:22

OBSID: 0x30011AB9

Comments: Test run out of sequence

Ran TOPE script with default values

QLA created file QLA-DCU-01_30011AB9.txt:

PHOTF: OBSID = 30011AB9, BBTYPE = 0x8800, APID = 0x505, SID = 0x200

Parameter	Initial	Final	Increment	Expect	Incre.	Packet Chars.
DCUFRAMECNT	0	100	100	100		Packet type = 0x15
TM3N	16383	99	49251	100		subtype = 0x1
FrameTime	53.7568	53.7568				Frame ID = 0x0 Frame Len = 0x126

STATISTICS ON TIME BETWEEN RECEPTION OF 2 CONSECUTIVE FRAMES:

mean = 53.75887 ms
sigma = 0.00154 ms

PHOTSW: OBSID = 30011AB9, BBTYPE = 0x8802, APID = 0x505, SID = 0x102

Parameter	Initial	Final	Increment	Expect	Incre.	Packet Chars.
DCUFRAMECNT	100	200	100	100		Packet type = 0x15
TM3N	99	133	34	34		subtype = 0x2
FrameTime	53.7568	53.7600				Frame ID = 0x2 Frame Len = 0x96

STATISTICS ON TIME BETWEEN RECEPTION OF 2 CONSECUTIVE FRAMES:

mean = 53.75890 ms
sigma = 0.00154 ms

PHOTMW: OBSID = 30011AB9, BBTYPE = 0x8803, APID = 0x505, SID = 0x103

Parameter	Initial	Final	Increment	Expect	Incre.	Packet Chars.
DCUFRAMECNT	200	300	100	100		Packet type = 0x15
TM3N	133	158	25	25		subtype = 0x2
FrameTime	53.7600	53.7600				Frame ID = 0x3 Frame Len = 0x66

STATISTICS ON TIME BETWEEN RECEPTION OF 2 CONSECUTIVE FRAMES:

mean = 53.75890 ms
sigma = 0.00152 ms



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PHOTLW: OBSID = 30011AB9, BBTYP E = 0x8804, APID = 0x505, SID = 0x104

Parameter	Initial	Final	Increment	Expect	Incr.	Packet Chars.
DCUFRAMECNT	300	400	100	100		Packet type = 0x15
TM3N	158	170	12	12		subtype = 0x2
FrameTime	53.7600	53.7600				Frame ID = 0x4 Frame Len = 0x36

STATISTICS ON TIME BETWEEN RECEPTION OF 2 CONSECUTIVE FRAMES:

mean = 53.75890 ms
sigma = 0.00152 ms

SPECF: OBSID = 30011AB9, BBTYP E = 0x8801, APID = 0x507, SID = 0x201

Parameter	Initial	Final	Increment	Expect	Incr.	Packet Chars.
DCUFRAMECNT	400	500	100	100		Packet type = 0x15
TM4N	16383	16	49168	17		subtype = 0x1
FrameTime	12.4928	12.4928				Frame ID = 0x1 Frame Len = 0x4E

STATISTICS ON TIME BETWEEN RECEPTION OF 2 CONSECUTIVE FRAMES:

mean = 12.49254 ms
sigma = 0.00089 ms

SPEC SW: OBSID = 30011AB9, BBTYP E = 0x8805, APID = 0x507, SID = 0x105

Parameter	Initial	Final	Increment	Expect	Incr.	Packet Chars.
DCUFRAMECNT	500	600	100	100		Packet type = 0x15
TM4N	16	28	12	12		subtype = 0x2
FrameTime	12.4928	12.4896				Frame ID = 0x5 Frame Len = 0x36

STATISTICS ON TIME BETWEEN RECEPTION OF 2 CONSECUTIVE FRAMES:

mean = 12.49254 ms
sigma = 0.00089 ms

SPEC LW: OBSID = 30011AB9, BBTYP E = 0x8806, APID = 0x507, SID = 0x106

Parameter	Initial	Final	Increment	Expect	Incr.	Packet Chars.
DCUFRAMECNT	600	700	100	100		Packet type = 0x15
TM4N	28	35	7	7		subtype = 0x2
FrameTime	12.4928	12.4928				Frame ID = 0x6 Frame Len = 0x1E

STATISTICS ON TIME BETWEEN RECEPTION OF 2 CONSECUTIVE FRAMES:

mean = 12.49254 ms
sigma = 0.00088 ms



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4.27 FUNC-DCU-02

Test Id:	FUNC-DCU-02
Initial Configuration:	DRCU_ON + AC/DC thermometry ON+MCU ON
Final Configuration:	DRCU_ON + AC/DC thermometry ON+MCU ON
Success Criteria:	<p>Test passed if DCUFRAMECNT goes from 700 to 1400 and the frametime difference between consecutive frames computed by QLA script is in agreement with the expected differences based on commanded sampling rate:</p> <ol style="list-style-type: none"> 1. Photometer Sampling rate is 15.3Hz → Δt ~ 65.5 ms 2. Spectrometer Sampling rate is 80Hz → Δt = 12.5 ms

Test Procedure:

Step#	Action	Comments
1	Write the current value of DCUFRAMECNT located d in DCU PARAMETERS AND	
2	Run QLA script FUNC-DCU-02.py on QLA console.	
3	Run FUNC-DCU-02 test procedure from the HCSS Test Procedure window on TOPE	
4	Write the current value of DCUFRAMECNT located d in DCU PARAMETERS AND	
5	Contingency: If test fails repeat steps 1 to 4.	

Test Log:

Test Id	Key Parameter(s)	Expected Value Before/After	Actual Value Before/After	Nb. of frames received	Test Result
FUNC-DCU-02	DCUFRAMECNT	m/m+1400	700 / 1400	700	Success

Start time @: 29/01/2007 - 14:26

End time @: 29/01/2007 - 14:29

OBSID: 0x30011ABA

Comments: Test run out of sequence

Contents of QLA created files show sampling times to be consistent with input parameters entered for sampling frequencies of photometer 18Hz (Δt ~ 53.3 ms) and spectrometer 80Hz Δt ~ 12.5 ms.



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4.28 FUNC-DCU-03

Test Id:	FUNC-DCU-03
Initial Configuration:	DRCU_ON + AC/DC thermometry ON+MCU ON
Final Configuration:	DRCU_ON + AC/DC thermometry ON+MCU ON
Success Criteria:	Test passed if : <ol style="list-style-type: none"> DCU produces 100 frames of Full Photometer Test Pattern and 100 frame of Full Spectrometer Test Pattern test. QLA analysis shows that phot/spec test patterns are the same as the reference phot/spec test patterns.

Test Procedure:

Step#	Action	Comments
1	Write the current value of DCUFRAMECNT located d in DCU PARAMETERS AND	
2	Run QLA script FUNC-DCU-03.py on QLA console.	
3	Run FUNC-DCU-03 test procedure from the HCSS Test Procedure window on TOPE	
4	Write the current value of DCUFRAMECNT located d in DCU PARAMETERS AND	
5	Contingency: If test fails repeat steps 1 to 4.	

Test Log:

Test Id	Key Parameter(s)	Expected Value Before/After	Actual Value Before/After	Nb. of frames received	Test Result
FUNC-DCU-03	DCUFRAMECNT	j/j+200	1400 / 1600	200	

Start time @: 29/01/2007 - 14:29

End time @: 29/01/2007 - 14:32

OBSID: 0x30011ABB

Comments: Test run out of sequence

Files produced by QLA:

QLA-DCU-03_30011ABB_8807.txt

QLA-DCU-03_30011ABB_8808.txt

Test pattern files show agreement with reference DCU test pattern files from OBSID 0x30011A6A (25/01/2007).



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4.29 FUNC-DCU-04P

Test Id:	FUNC-DCU-04P
Initial Configuration:	DRCU_ON + AC/DC thermometry ON+MCU ON
Final Configuration:	DRCU_ON + AC/DC thermometry ON+MCU ON + Photometer LIAs ON
Success Criteria:	Test passed if : <ol style="list-style-type: none"> 1. SCUDCDCSTAT parameter goes from 4 to 5. 2. Photometer LIA card voltages are showing correct readings of +5V,+9V,-9V. 3. Photometer LIA temperatures show an increase indicating that they are ON.

Test Procedure:

Step#	Action	Comments
1	On QLA bring up a time series display of the HK parameters: PLIAP5V PLIAP9V PLIAM9V LIAP1/2/3/4/5/6/7/8/9TEMP	
2	Run FUNC-DCU-04P test procedure from the HCSS Test Procedure window on TOPE	
5	Contingency: If test fails repeat steps 1 and 2.	

Test Log:

Test Id	Key Parameter(s)	Expected Value Before/After	Actual Value Before/After	Nb. of frames received	Test Result
FUNC-DCU-04-P	SCUDCDCSTAT PLIAP5V PLIAP9V PLIAM9V LIAP1TEMP to LIAP9TEMP	4/5 0/~ +5V 0/~+11V 0/~-11V N/A/ [290-300]K	4/5 0/+5.18V 0/+11.53V 0/-11.53V ~294/warming up		Success

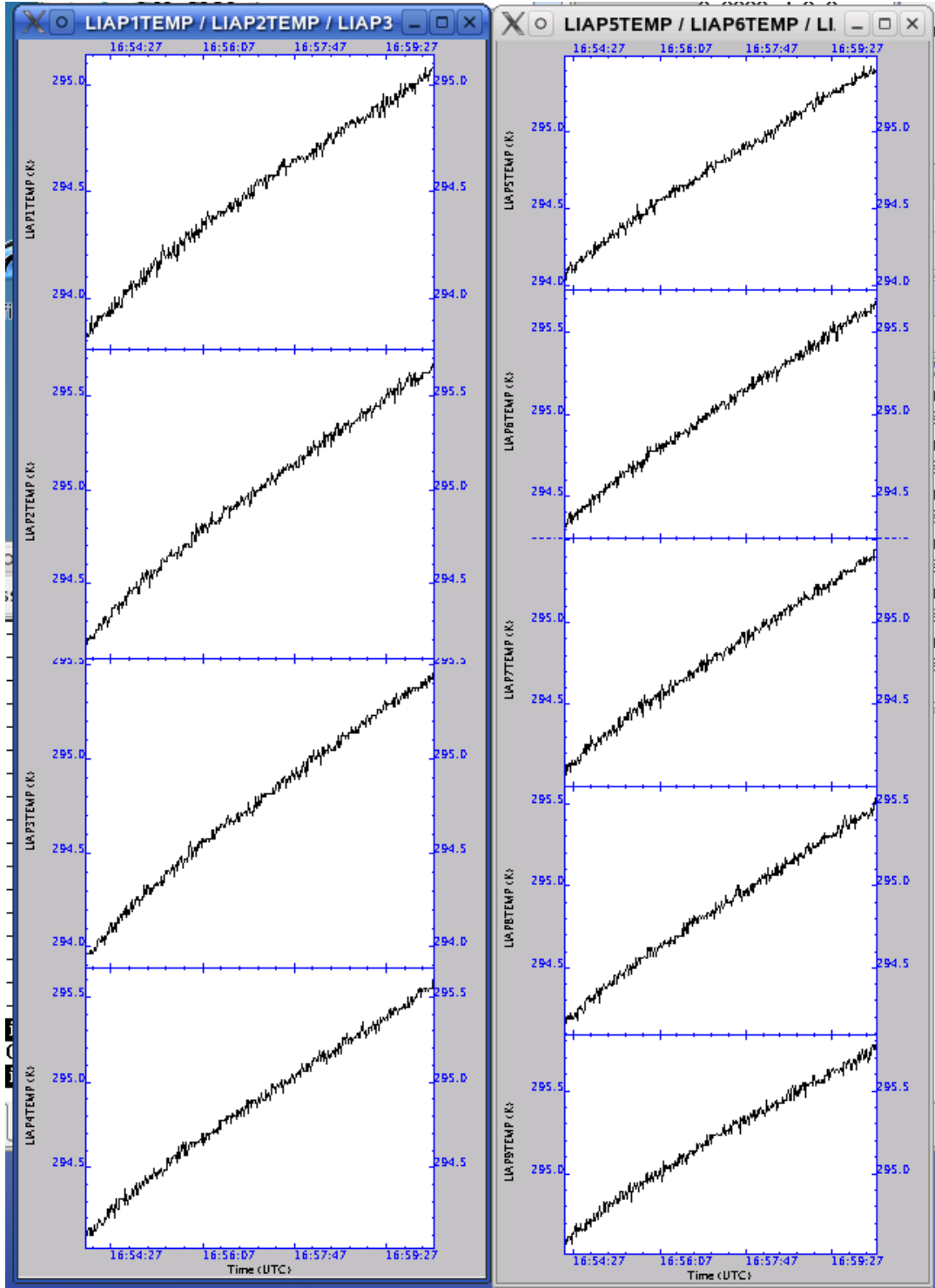


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Start time @: 16:53
End time @: 16:54
OBSID: 0x30011AAB
Comments:





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4.30 FUNC-DCU-11P

Test Id:	FUNC-DCU-11P
Initial Configuration:	DRCU_ON + AC/DC thermometry ON+MCU ON+ Photometer LIAs ON
Final Configuration:	DRCU_ON + AC/DC thermometry ON+MCU ON+ Photometer LIAs ON + Photometer BIAS ON +Photometer JFETs ON
Success Criteria:	Test passed if Photometer JFET source and drain voltages are correct: <ol style="list-style-type: none"> 1. PSWJFETVSS1/2/3/4/5/6 (RAW: 0x4C CONVERTED ~ -1.5V). 2. PMLWJFETVSS1/2/3/4 (RAW: 0x4C CONVERTED ~ -1.5V). 3. PSWJFETSTAT = 0x3F 4. PMLWJFETSTAT = 0x1F

Test Procedure:

Step#	Action	Comments
1	Run FUNC-DCU-11P test procedure from the HCSS Test Procedure window on TOPE	
2	After the test Write the values RAW and converted values of: PSWJFETSTAT,PMLWJFETSTAT, PSWJFET1/2/3/4/5/6V PMWJFET1/2/3/4V PLWJFET1/2V located in DCU PARAMETERS AND	
3	Contingency: If test fails repeat steps 1 and 2.	

Test Log:

Test Id	Key Parameter(s)	Expected Value Before/After	Actual Value Before/After	Nb. of frames received	Test Result
FUNC-DCU-11P	PSWJFETSTAT PMLWJFETSTAT PSWJFET1/2/3/4/5/6V PMWJFET1/2/3/4V PLWJFET1/2V	0/0x3f 0/0x7f 0V/-1.5V 0V/-1.5V 0V/-1.5V	0/0x03f 0/0x07f See comments	N/A	Success



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Start time @: 17:05
End time @: 17:06
OBSID: 0x30011AAC

Comments:

The Vss values for the JFETs were the same as for the PFM4 cold test campaign, i.e.

PSWJFET1V: -1.68V
PSWJFET2V: -1.59V
PSWJFET3V: -1.37V
PSWJFET4V: -1.59V
PSWJFET5V: -1.78V
PSWJFET6V: -1.59V

PMWJFET1V: -1.68V
PMWJFET2V: -1.59V
PMWJFET3V: -1.59V
PMWJFET4V: -1.88V

PLWJFET1V: -1.59V
PLWJFET2V: -1.37V

PSW:

G8 and C12 have a relatively higher output (~ 45000 ADUs against ~ 16500) than the rest
G13 appears to be dead (no signal before or after, only during the JFET switch on did it show a spike).

PMW:

D7, C8, DP1, T2 are flat at 0 ADUs

PLW:

All good



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4.31 FUNC-DCU-13P

Test Id:	FUNC-DCU-13P
Initial Configuration:	DRCU_ON + AC/DC thermometry ON+MCU ON+ Photometer LIAs ON + Photometer BIAS ON +Photometer JFETs ON
Final Configuration:	DRCU_ON + AC/DC thermometry ON+MCU ON+ Photometer LIAs ON + Photometer BIAS ON +Photometer JFETs ON
Success Criteria:	Test passed if : The photometer detectors show a small linear variation on the output voltage when different bias is applied through the load curve.

Test Procedure:

Step#	Action	Comments
1	On QLA bring up a time series display of a couple of pixels on each of the photometer BDAs	
2	Run FUNC-DCU-13P test procedure from the HCSS Test Procedure window on TOPE	
3	Contingency: If test fails repeat step 1 and 2.	

Test Log:

Test Id	Key Parameter(s)	Expected Value Before/After	Actual Value Before/After	Nb. of frames received	Test Result
FUNC-DCU-13P				N/A	Success



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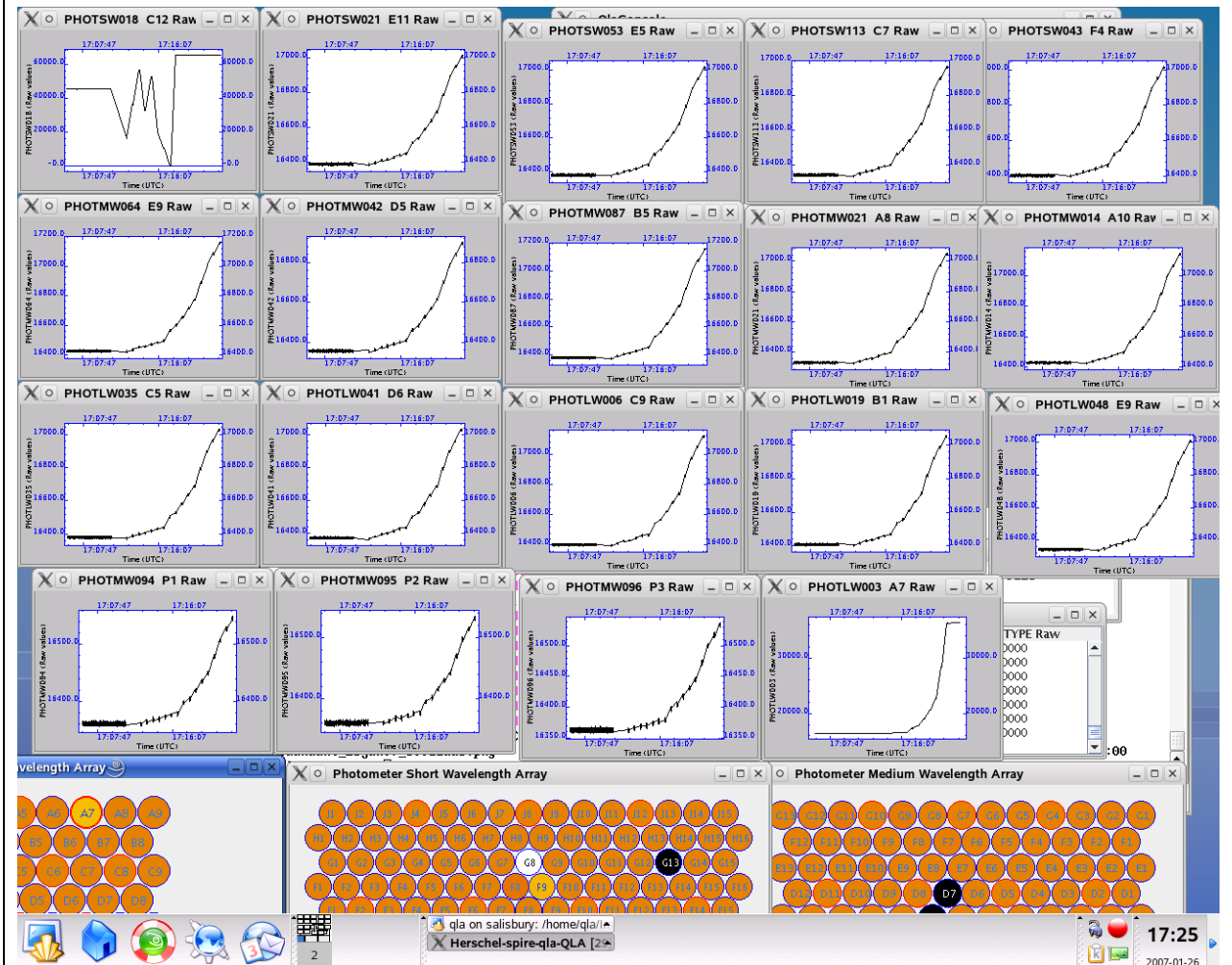
Start time @: 17: 12
End time @: 17: 24
OBSID: 0x30011AAD

Comments:

Parameter for LC:

Array: PF
Bias frequency: 130 Hz
Sampling frequency: 18 Hz
PSW phase: 180.71 deg
PMW phase: 180.71 deg
PLW phase: 180.71 deg
Time at each level: 5 s

See Annex 2 for detailed plots for each pixel





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4.32 ILT_PERF_DNA_P

Test Id:	
Initial Configuration:	DRCU_ON + AC/DC thermometry ON+MCU ON + Photometer LIAs ON + Photometer BIAS ON + Photometer JFETs ON
Final Configuration:	DRCU_ON + AC/DC thermometry ON+MCU ON + Photometer LIAs ON + Photometer BIAS ON + Photometer JFETs ON
Success Criteria:	Test passed if : The Photometer detectors don't show excess noise.

Test Procedure:

Step#	Action	Comments
1	Run ILT-PERF-DAN-P test procedure from the HCSS Test Procedure window on TOPE	
2	Contingency: If test fails repeat step 1.	

Test Log:

Test Id	Key Parameter(s)	Expected Value Before/After	Actual Value Before/After	Nb. of frames received	Test Result
ILT_PERF_DNA_P				N/A	

Start time @: 17: 30
End time @: 17: 35
OBSID: 0x30011AAE

Comments:

Detectors settings:

Bias frequency: 130 Hz
 Sampling frequency: 18 Hz
 PSW phase: 180.71 deg
 PMW phase: 180.71 deg
 PLW phase: 180.71 deg
 PSW bias : ~ 31mV
 PMW bias : ~ 31mV
 PLW bias : ~ 31mV
 TC bias : ~ 62 mV

Duration of test: 5 minutes



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Step#	Action	Comments
1	From TOPE HCSS Test Procedures run PDET-OFF	Executed @ 17:36 OBSID 0x30011AAF



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4.33 FUNC-DCU-04S

Test Id:	FUNC-DCU-04S
Initial Configuration:	DRCU_ON + AC/DC thermometry ON+MCU ON
Final Configuration:	DRCU_ON + AC/DC thermometry ON+MCU ON + Spectrometer LIAs ON
Success Criteria:	Test passed if : <ol style="list-style-type: none"> 1. SCUDCDCSTAT parameter goes from 4 to 6. 2. Spectrometer LIA card voltages are showing correct readings of +5V,+9V,-9V. 3. Spectrometer LIA temperatures show an increase indicating that they are ON.

Test Procedure:

Step#	Action	Comments
1	On QLA bring up a time series display of the HK parameters: SLIAP5V SLIAP9V SLIAM9V LIAS1/2/3TEMP	
2	Run FUNC-DCU-04S test procedure from the HCSS Test Procedure window on TOPE	
5	Contingency: If test fails repeat steps 1 and 2.	

Test Log:

Test Id	Key Parameter(s)	Expected Value Before/After	Actual Value Before/After	Nb. of frames received	Test Result
FUNC-DCU-04S	SCUDCDCSTAT SLIAP5V SLIAP9V SLIAM9V LIA1/2/3TEMP	4/6 0/~ +5V 0/~+11V 0/~-11V N/A/ [290-300]K	4/6 0.17 / 5.23 0.003/ 11.57 0.003/-11.55 /~-295Kwarming up		Success

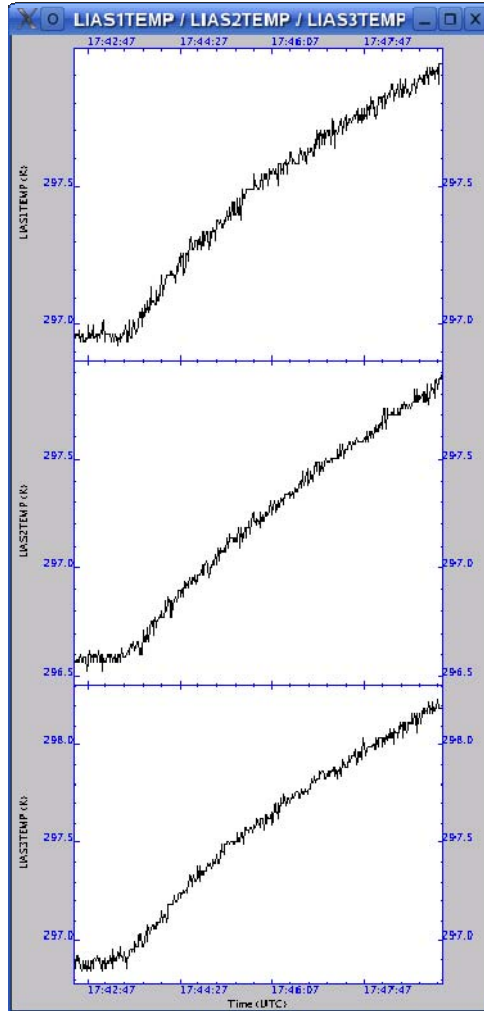


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Start time @: 17:43
End time @: 17:44
OBSID: 0x30011AB0
Comments:



Spectrometer LIAs switched ON correctly



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4.34 FUNC-DCU-11S

Test Id:	FUNC-DCU-11S
Initial Configuration:	DRCU_ON + AC/DC thermometry ON+MCU ON + Spectrometer LIAs ON
Final Configuration:	DRCU_ON + AC/DC thermometry ON+MCU ON + Spectrometer LIAs ON + Spectrometer BIAS ON + Spectrometer JFETs ON
Success Criteria:	Test passed if SCUDCDCSTAT goes from 4 to 6, Spectrometer LIAs voltages are correct and SJFET voltages are also correct.

Test Procedure:

Step#	Action	Comments
1	Run FUNC-DCU-11S test procedure from the HCSS Test Procedure window on TOPE	
2	After the test Write the values RAW and converted values of: LIASTAT SLIAP5V, SLIAP9V, SLIAM9V, SSWJFETSTAT,SLWJFETSTAT, SSWJFET1V,SLWJFET2V located in DCU PARAMETERS AND	
3	Contingency: If test fails repeat steps 1 and 2.	

Test Log:

Test Id	Key Parameter(s)	Expected Value Before/After	Actual Value Before/After	Nb. of frames received	Test Result
FUNC-DCU-11S	SCUDCDCSTAT LIASTAT SLIAP5V SLIAP9V SLIAM9V SPECJFETSTAT SSWJFET1/2V SLWJFET1/2V	6/6 0/0 0V/ ~ 5V 0V/~11V 0V/-11V 0/7 0V/-1.5V 0V/-1.5V	6/6 0/0 /5.23 /11.57 /-11.55 0/0x7 See comments below	N/A	Success



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Start time @: 17:51
End time @: 17:52
OBSID: 0x30011AB1

Comments:

The Vss values for the JFETs were the same as for the PFM4 cold test campaign, i.e.

SSWJFET1V: -2.07V

SSWJFET2V: -1.59V

SLWJFET1V: -1.68V

SSW:

D7 shows a higher output (~ 35000 ADUs against ~ 16500 ADUs) then the rest of the array.

SLW:

DP1, DP2 not responsive after switch on, they jump to zero. T2 remains at zero.

C2, C4 and B3 showing previous (PFM4) anomalous behaviour. C4 behaviour corrected itself during cooldown.



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4.35 FUNC-DCU-13S

Test Id:	FUNC-DCU-13S
Initial Configuration:	DRCU_ON + AC/DC thermometry ON+MCU ON + Spectrometer LIAs ON + Spectrometer BIAS ON + Spectrometer JFETs ON
Final Configuration:	DRCU_ON + AC/DC thermometry ON+MCU ON + Spectrometer LIAs ON + Spectrometer BIAS ON + Spectrometer JFETs ON
Success Criteria:	Test passed if : The spectrometer detectors show a small linear variation on the output voltage when different bias is applied through the load curve.

Test Procedure:

Step#	Action	Comments
1	Run FUNC-DCU-13S test procedure from the HCSS Test Procedure window on TOPE	
2	Contingency: If test fails repeat step 1.	

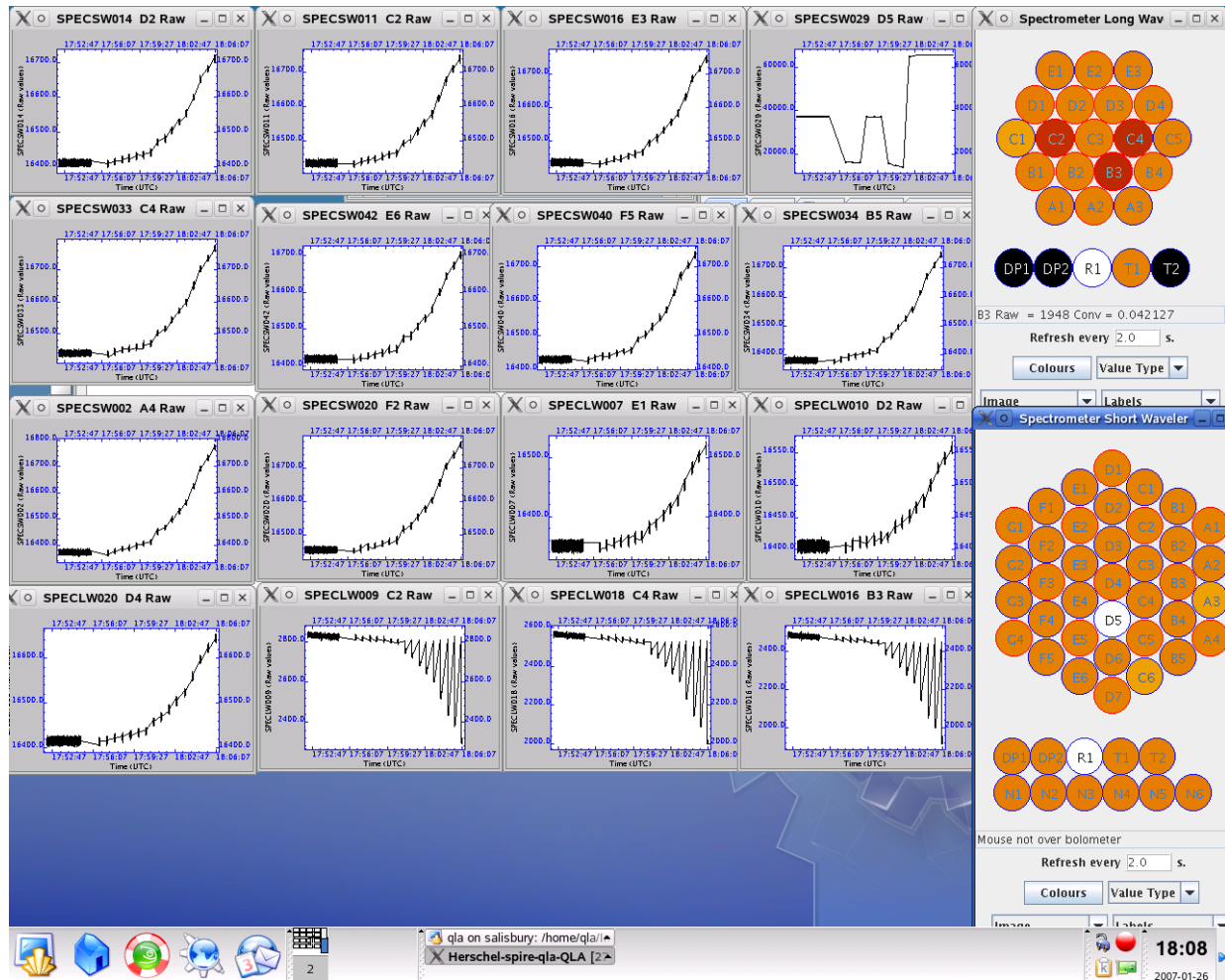
Test Log:

Test Id	Key Parameter(s)	Expected Value Before/After	Actual Value Before/After	Nb. of frames received	Test Result
FUNC-DCU-13S				N/A	Success

Start time @: 17:56
End time @: 18:10
OBSID: 0x30011AB2

Comments:

Array: SF
 Bias frequency: 160 Hz
 Sampling frequency: 80 Hz
 SSW phase shift: 180.71deg
 SLW phase shift: 179.295 deg
 Time at each level: 5 s



SSW D5 shows different behaviour than the rest of the pixels as in PFM4.
 Generally all (SSW/SLW) pixels looking responsive (TBC) except SSW C2,C4,B3 (the three bottom last ones).

See Annex 2 for detailed plots for every pixel.



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4.36 ILT_PERF_DNA_S

Test Id:	FUNC-DCU-13S
Initial Configuration:	DRCU_ON + AC/DC thermometry ON+MCU ON + Spectrometer LIAs ON + Spectrometer BIAS ON + Spectrometer JFETs ON
Final Configuration:	DRCU_ON + AC/DC thermometry ON+MCU ON + Spectrometer LIAs ON + Spectrometer BIAS ON + Spectrometer JFETs ON
Success Criteria:	Test passed if : The spectrometer detectors show a signal with some noise.

Test Procedure:

Step#	Action	Comments
1	Run FUNC-DCU-13S test procedure from the HCSS Test Procedure window on TOPE	
2	Contingency: If test fails repeat step 1.	

Test Log:

Test Id	Key Parameter(s)	Expected Value Before/After	Actual Value Before/After	Nb. of frames received	Test Result
ILT_PERF_DNA_S				N/A	

Start time @: 18:11
End time @: 18:16
OBSID: 0x30011AB3

Comments:

Test run in order to collect noise data at nominal spectrometer settings:

- Array: SF
- Bias frequency: 160 Hz
- Sampling frequency: 80 Hz
- SSW phase shift: 180.71deg
- SLW phase shift: 179.29 deg

Duration of test: 5 minutes

QLA script needed to report the RMS values for all Spectrometer detectors.

Step#	Action	Comments
1	From TOPE HCSS Test Procedures run SDET_OFF	18:45 OBSID 0x30011A74



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SWITCH OFF sequence:

Execute MCU_OFF
Execute DRCU_OFF

Power OFF DRCU
Power OFF DPU

5. ANNEXE1 (INSTRUMENT NOMINAL CONFIGURATION/MODES)

	OFF	INI T	DPU_O N	DRCU_O N	REDY	PHOT STBY	SPEC STBY	CREC	SAFE
DPU		ON	ON	ON	ON	ON	ON	ON	ON
Essential Hsk packets			0.5Hz	0.5Hz	0.5Hz	0.5Hz	0.5Hz	0.5Hz	0.5Hz
Normal Hsk packets			1.0Hz	1.0Hz	0.25Hz	0.25Hz	0.25Hz	1.0Hz	0.25Hz
TC Acceptance		TB C	Yes	Yes	Yes	Yes	Yes	Yes	Yes
Event packets		Yes	Yes	Yes	Yes	Yes	Yes	Yes	Yes
Science packets									
VM								Cooler_Recycle	
VM1						Det_Temp_C trl			
VM2									
VM3									
MODE			0x0000	0x0100	0x0200	0x0300	0x0400	0x0600	0x0900
DRCU			ON	ON	ON	ON	ON	ON	
SCU									
Temp Channels powered					Yes	Yes	Yes	Yes	
SubK Channel powered					Yes	Yes	Yes	Yes	
PCAL source powered									
SCAL sources powered							TBD		
TC Heater powered						Yes			
Cooler SP Heater powered								Yes	
Cooler EV HS powered								Yes	
Cooler SP HS powered					Yes	Yes	Yes	Yes	
DCU									
Photometer BIAS						Yes			
Photometer JFETS						Yes			
Photometer LIAs						Yes			
TC BIAS						Yes			
TC JFETS						Yes			
TC LIAs						Yes			
Spectrometer BIAS							Yes		
Spectrometer JFETS							Yes		
Spectrometer LIAs							Yes		
MCU									
DSP					On	On	On	On	
BSM						Hold	Hold		
SMEC							Hold		

6. ANNEXE 2 (RESULTS OF LOAD CURVES)

The following graphs (1-12) show the response of the 288 Photometer detectors to the input voltage during the Load Curve (FUNC-DCU-13). The graph (13) shows the response of the 3 PTC channels to the input voltage during the Load Curve. The graphs (14-16) show the spectrometer 78 detectors output voltage during the load curve performed on the spectrometer side. These plots are for OBSIDs 30011AAD (phot) and 30011AB2 (spec).

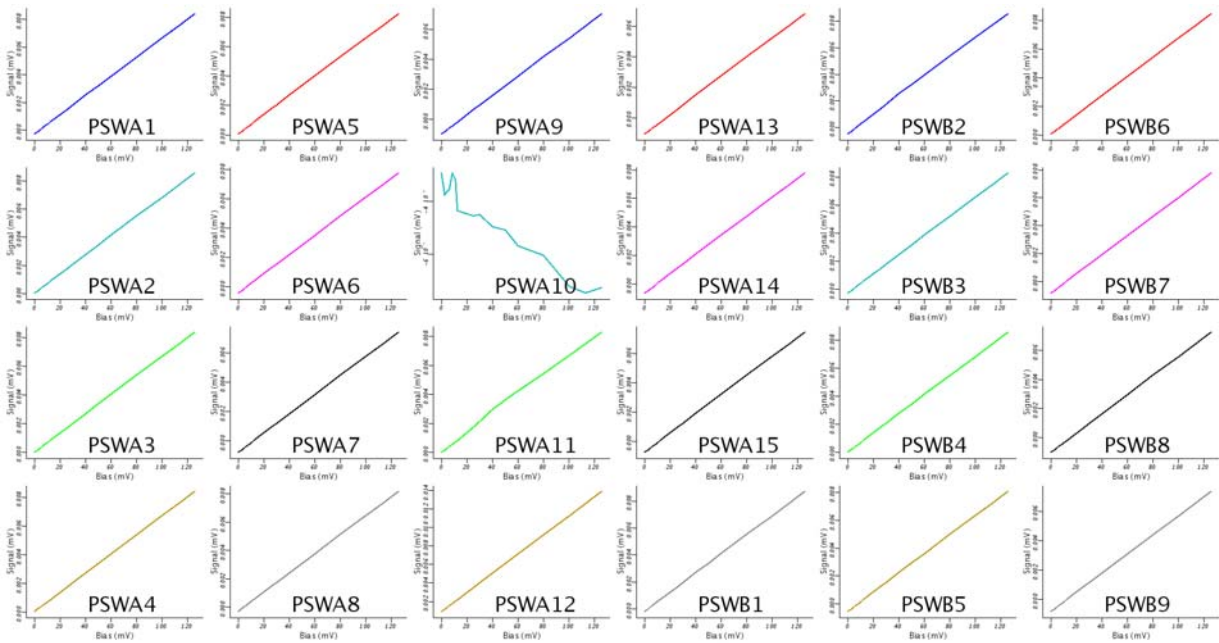


Figure 1. PSW Detectors (1)

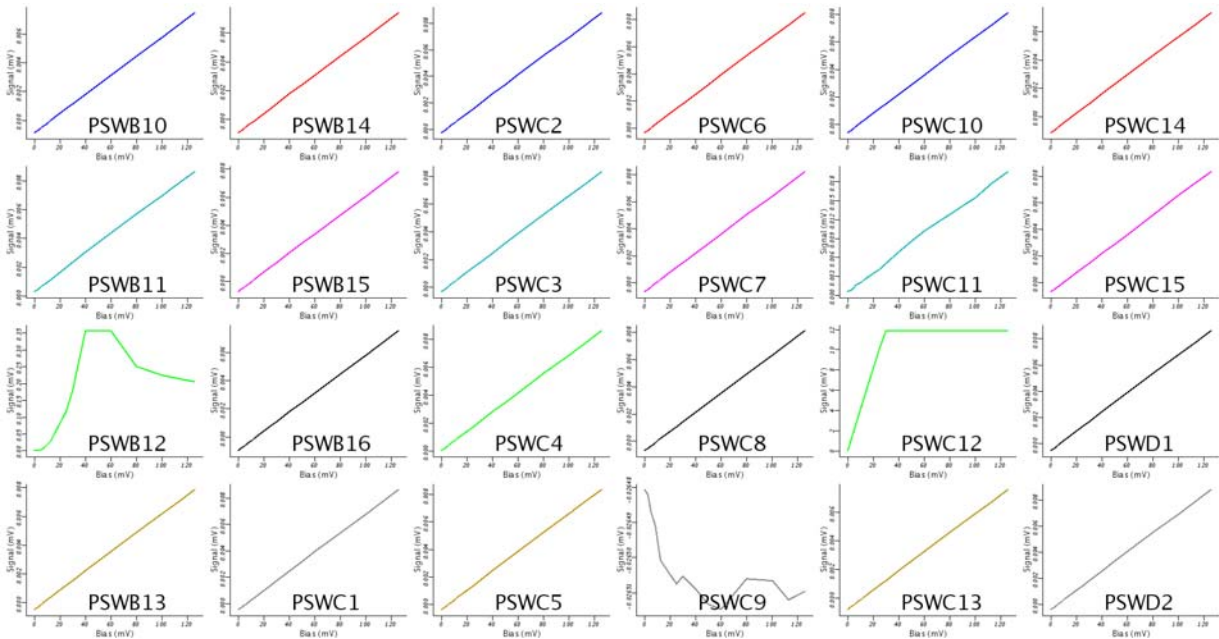


Figure 2. PSW Detectors (2)

PFM5 WARM FUNCTIONAL TEST REPORT
Redundant Side
A.A.Aramburu

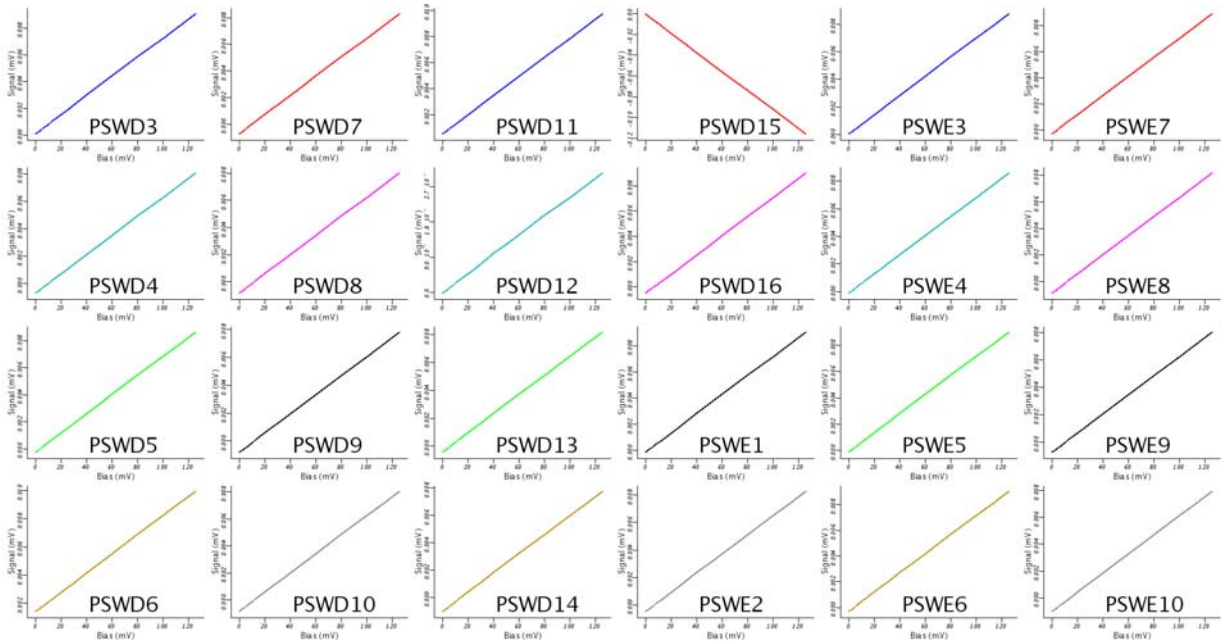


Figure 3. PSW Detectors (3)

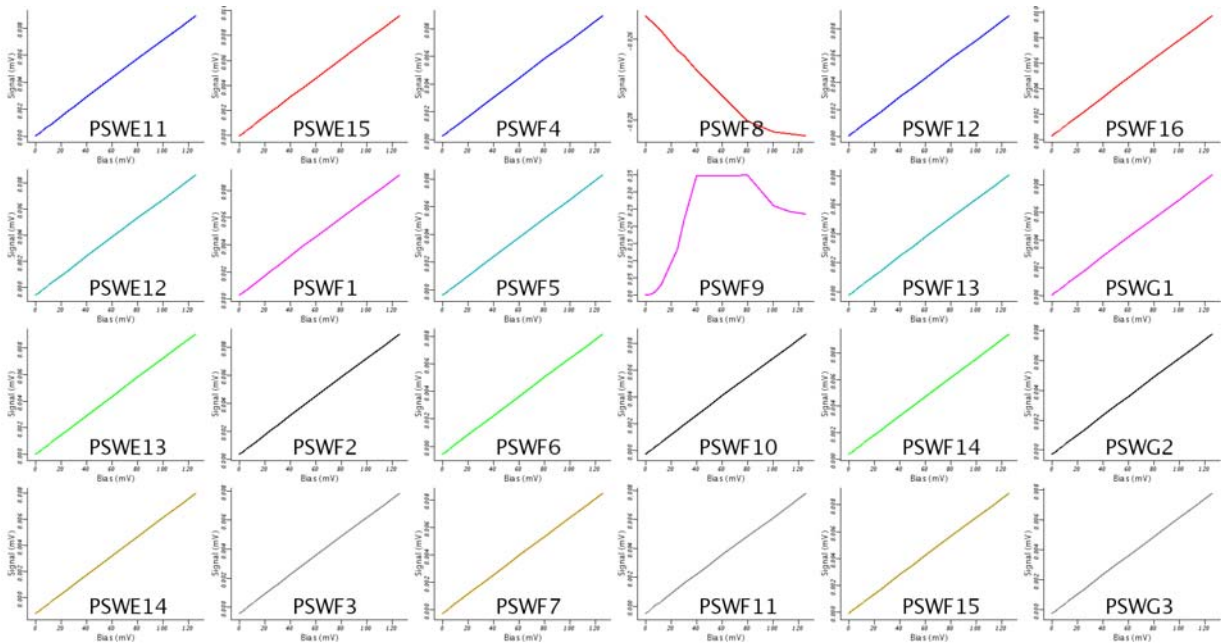


Figure 4. PSW Detectors (4)

**PFM5 WARM FUNCTIONAL TEST REPORT
Redundant Side
A.A.Aramburu**

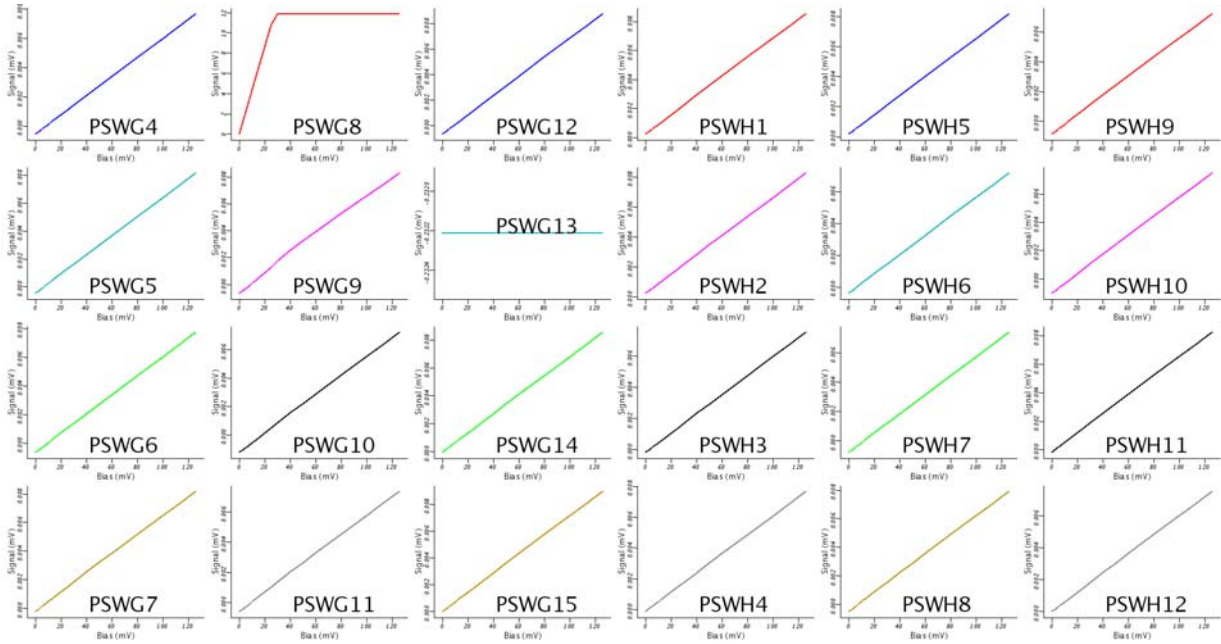


Figure 5. PSW Detectors (5)

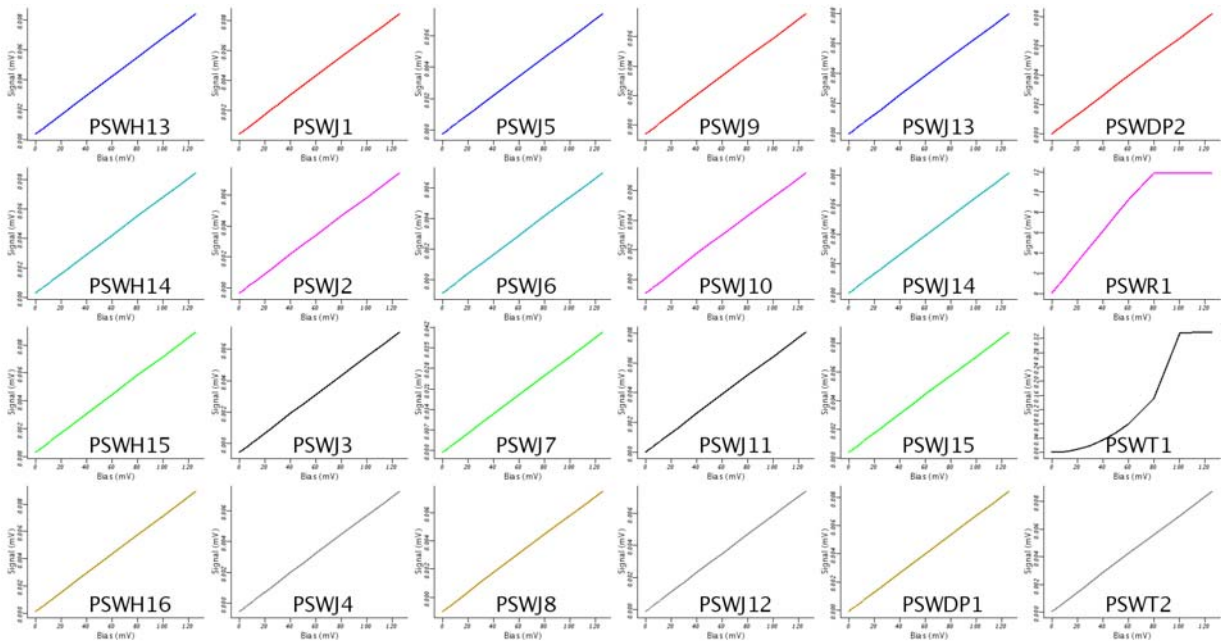


Figure 6. PSW Detectors (6)



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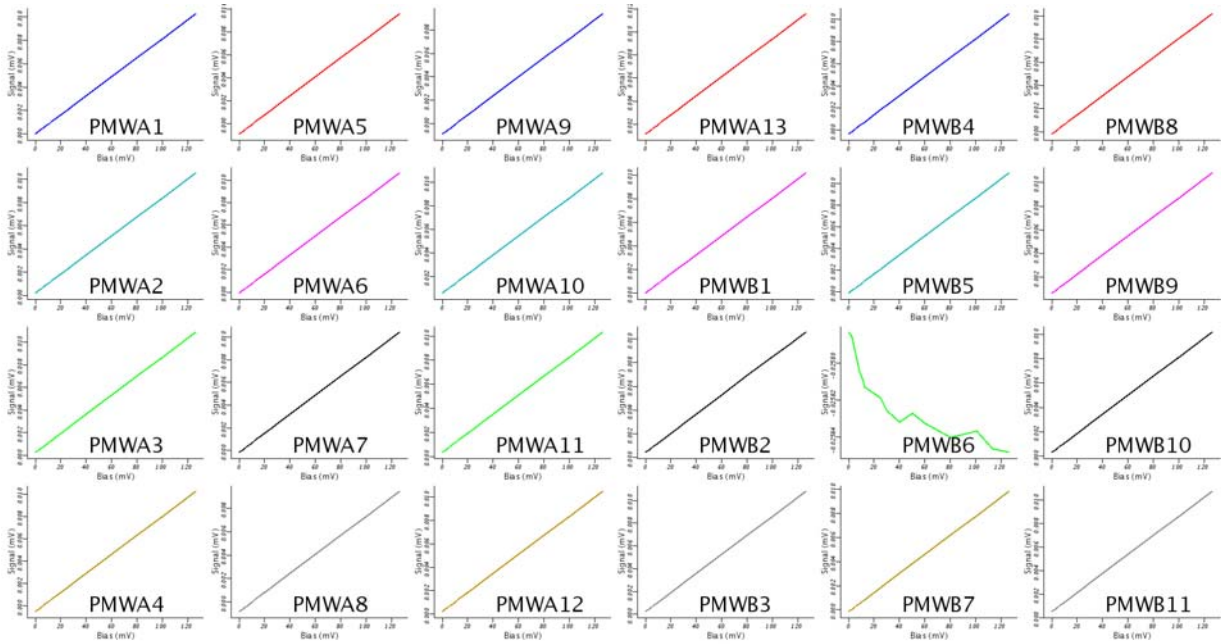


Figure 7. PMW Detectors (1)

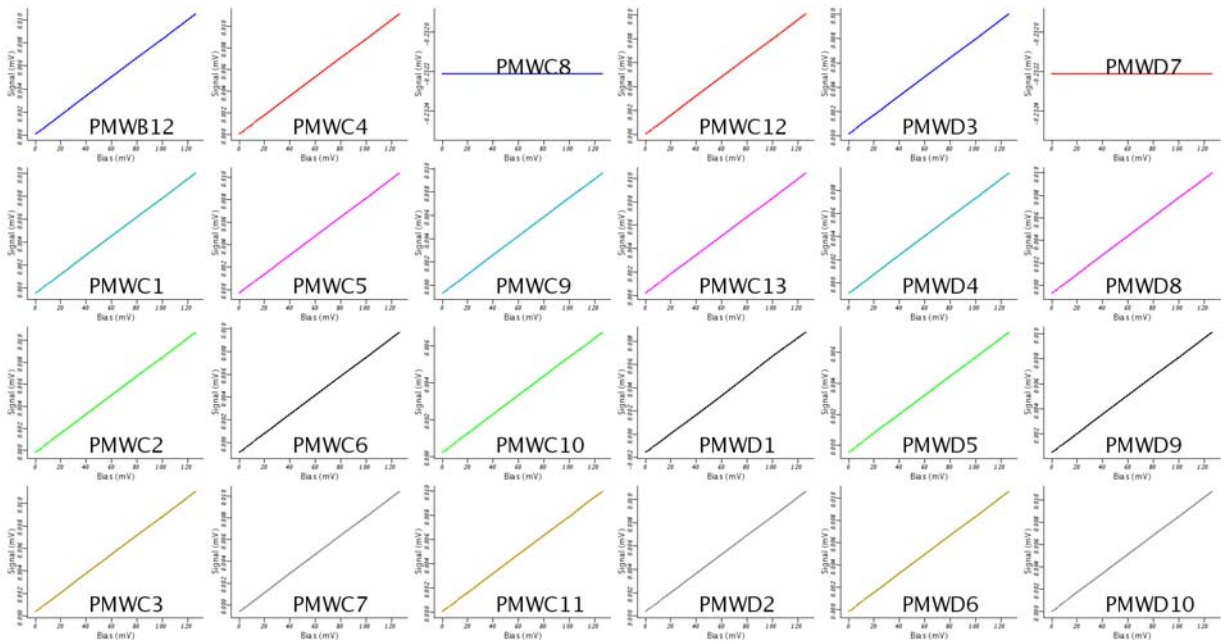


Figure 8. PMW Detectors (2)



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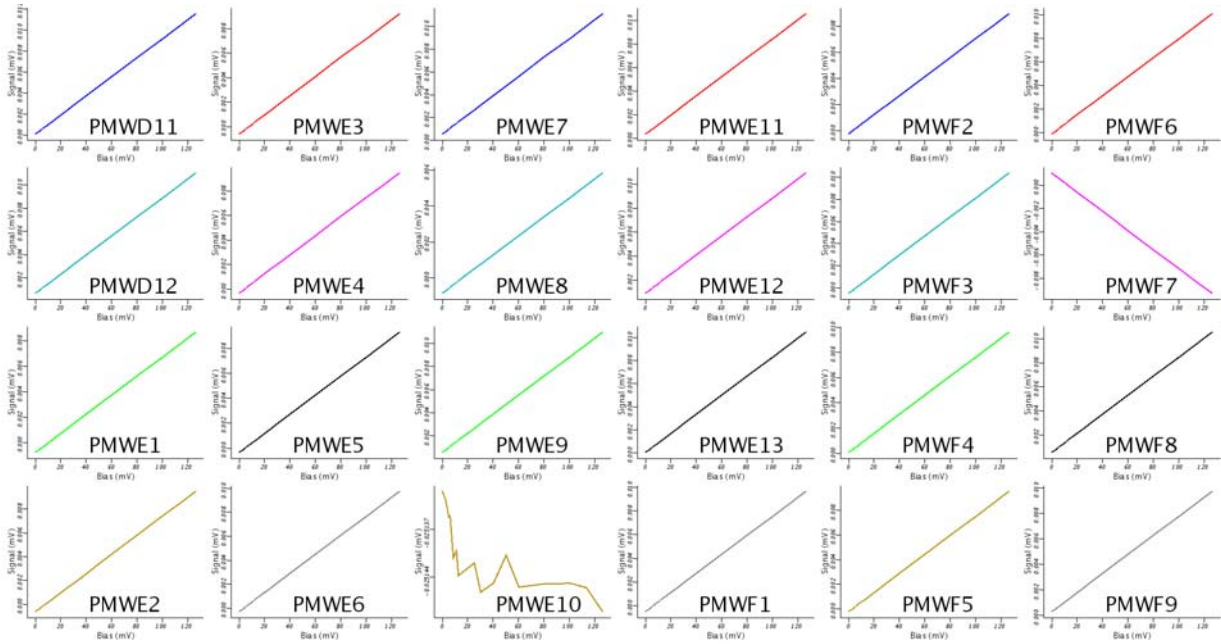


Figure 9. PMW Detectors (3)

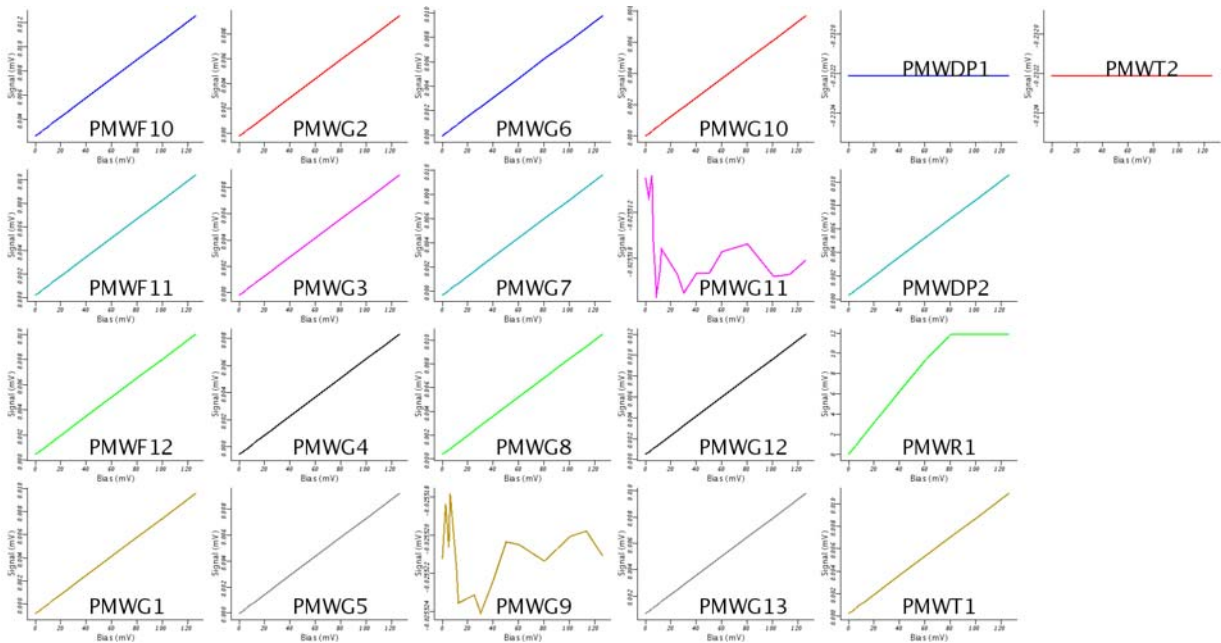


Figure 10. PMW Detectors (4)



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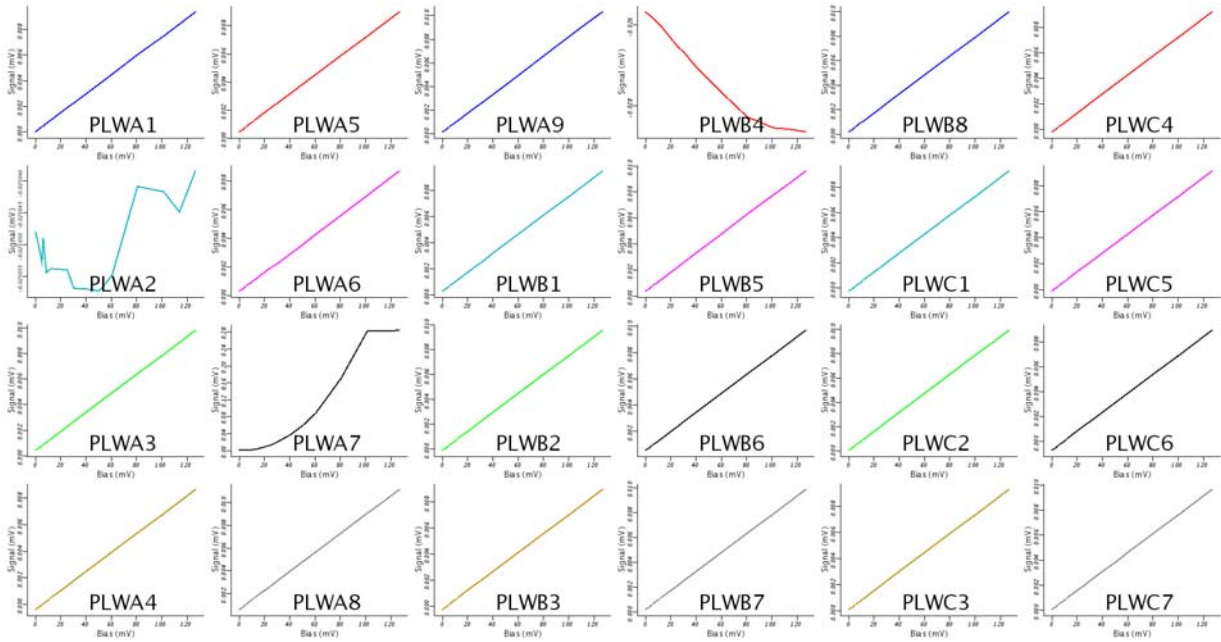


Figure 11. PLW Detectors (1)

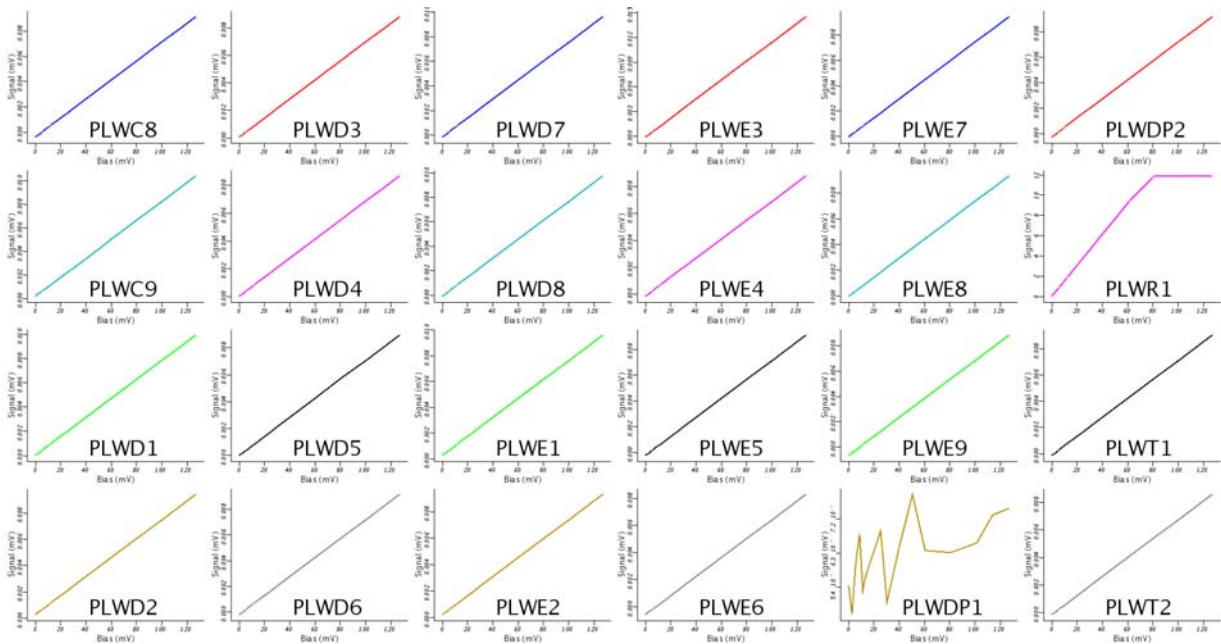


Figure 12. PLW Detectors (2)



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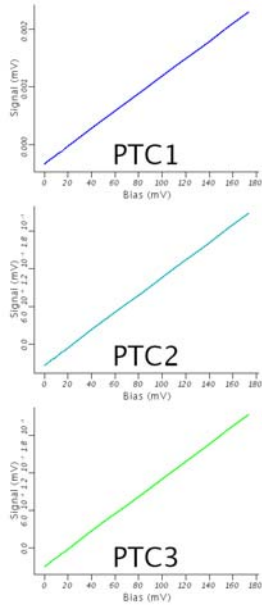


Figure 13. PTC Detectors (1)

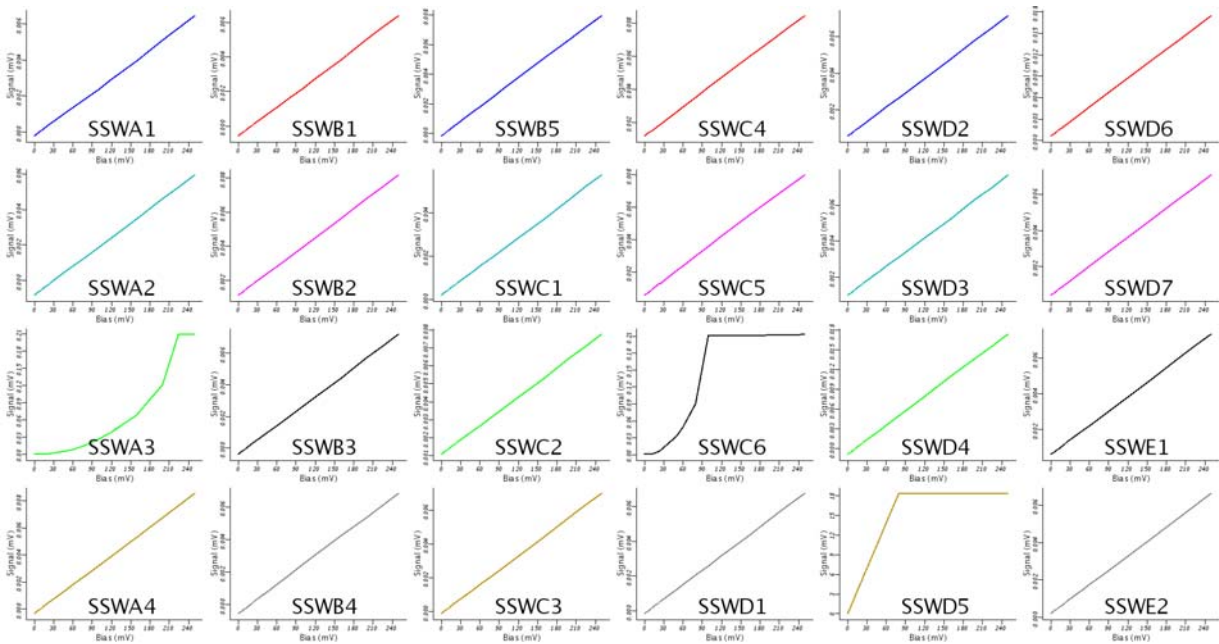


Figure 14. SSW Detectors (1)



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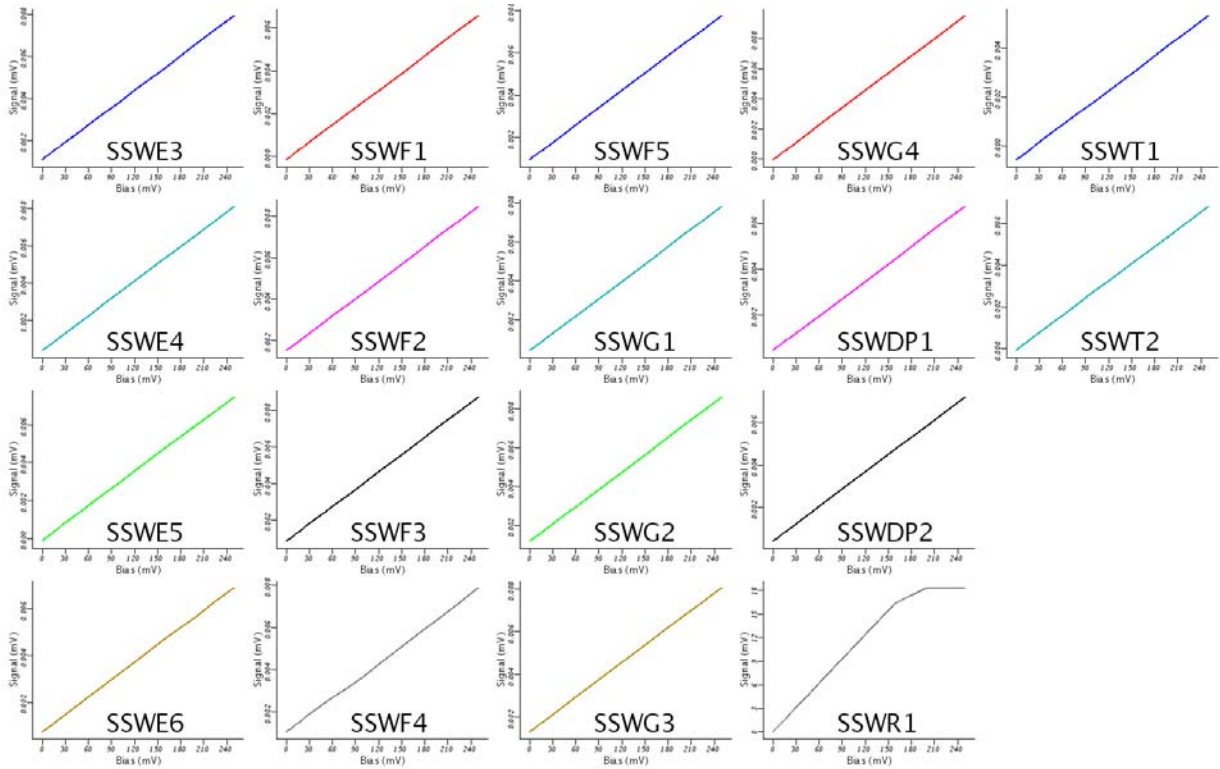


Figure 135. SSW Detectors (2)

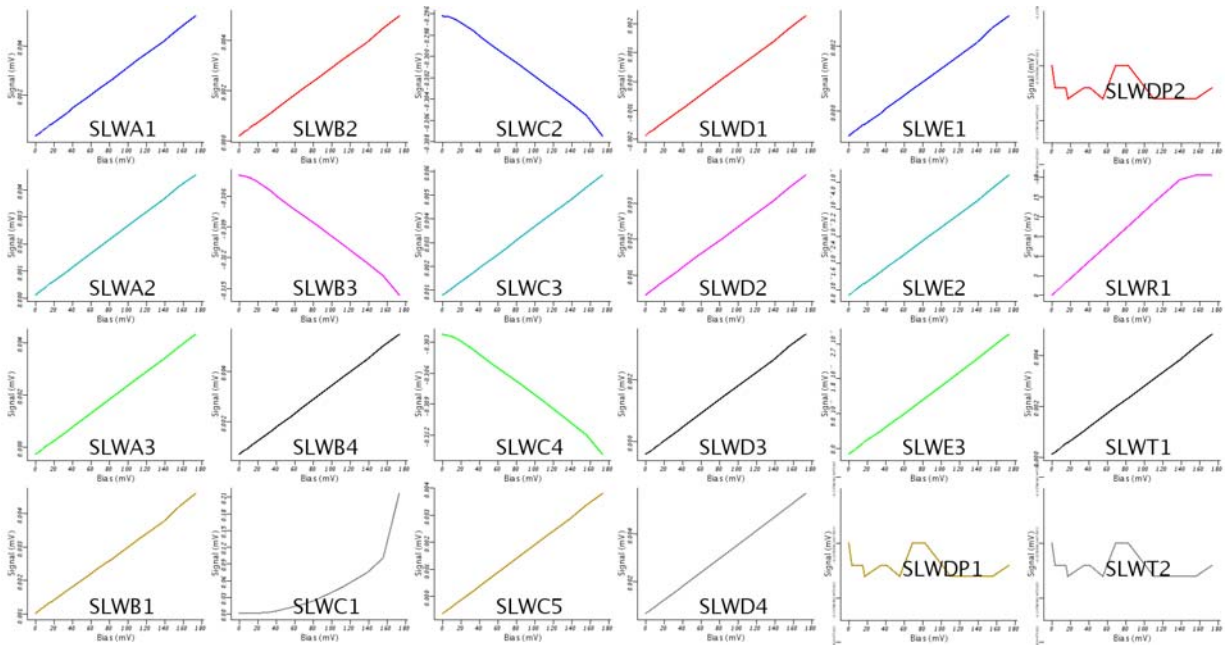


Figure 146. SLW Detectors (1)